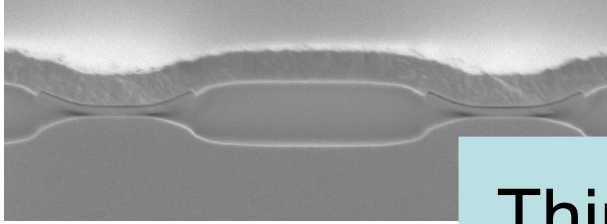


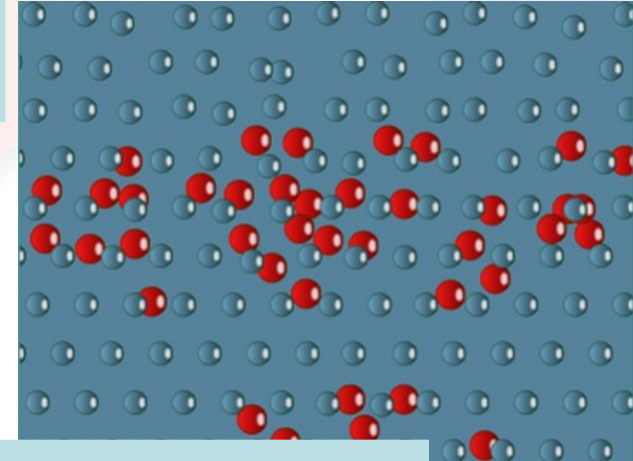
# Wafer Fabrication Part II

- Introduction to TMEC
- History from Edison's Light Bulb to Pentium 4
- Semiconductor Materials
- Wafer Preparation
- **Wafer Fabrication Processes**
- Thin Film Deposition Process
- Patterning Process
- Etching Process
- Doping Process
- Contamination

# Microelectronics Fabrication



Thin Film Deposition

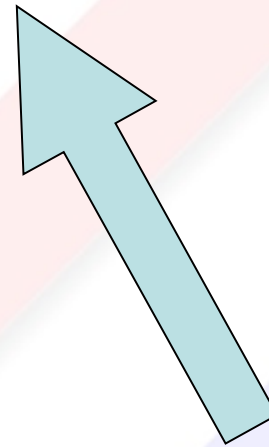
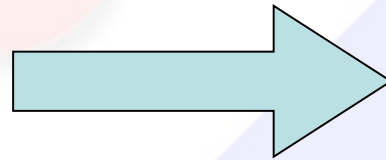
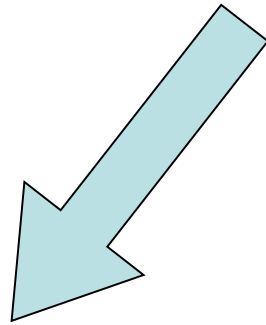
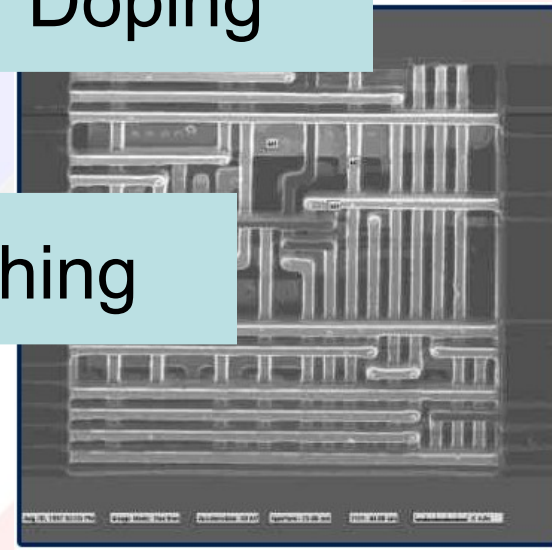


Doping

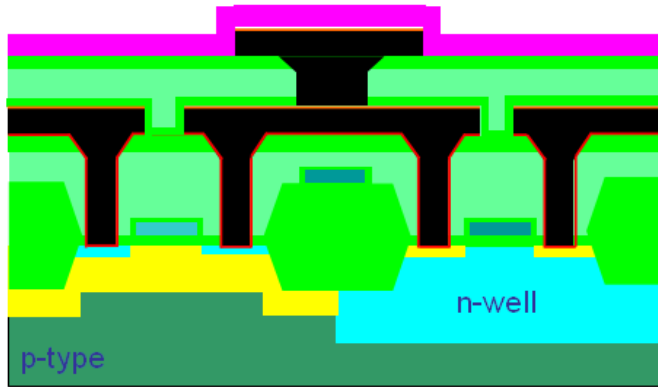
Lithography



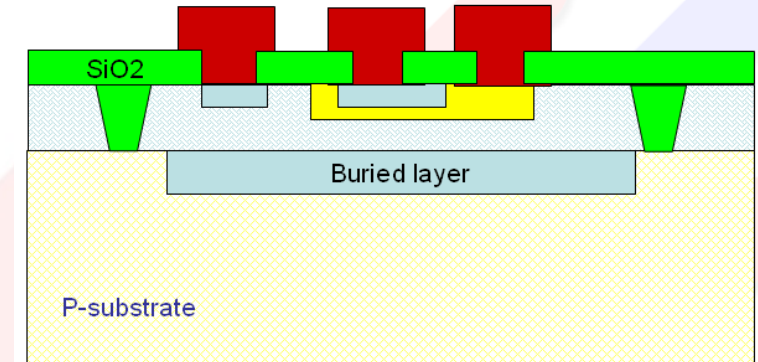
Etching



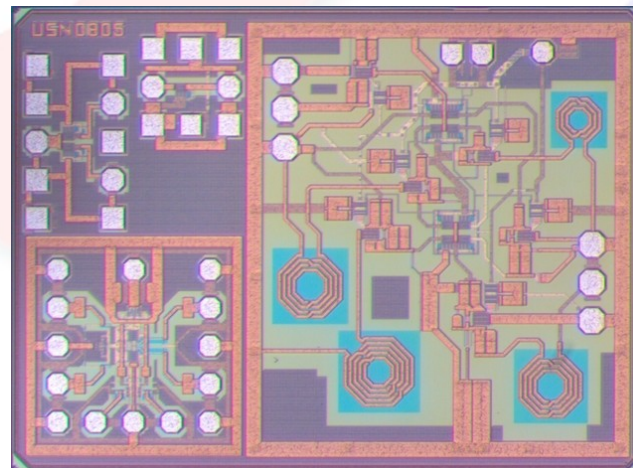
# Wafer Fabrication Processes



CMOS Process



Bipolar Process



BiCMOS Process

Technologie 0.25µm BiCMOS  
SiGe, Philips

## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation



p-type Cz wafer

p-type

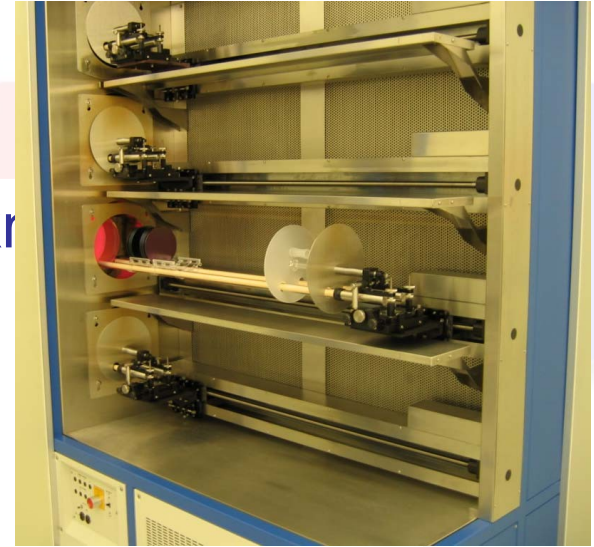
## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

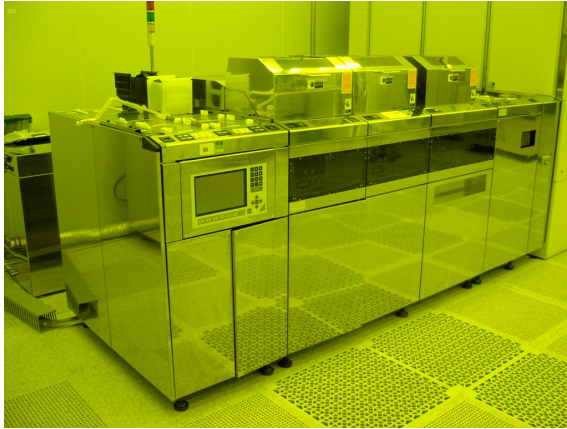


# n-well

Initial oxidation: O /H (Thickness  
420 nm)







## Photolithography : NWELL

Photoresist (PR)

p-type

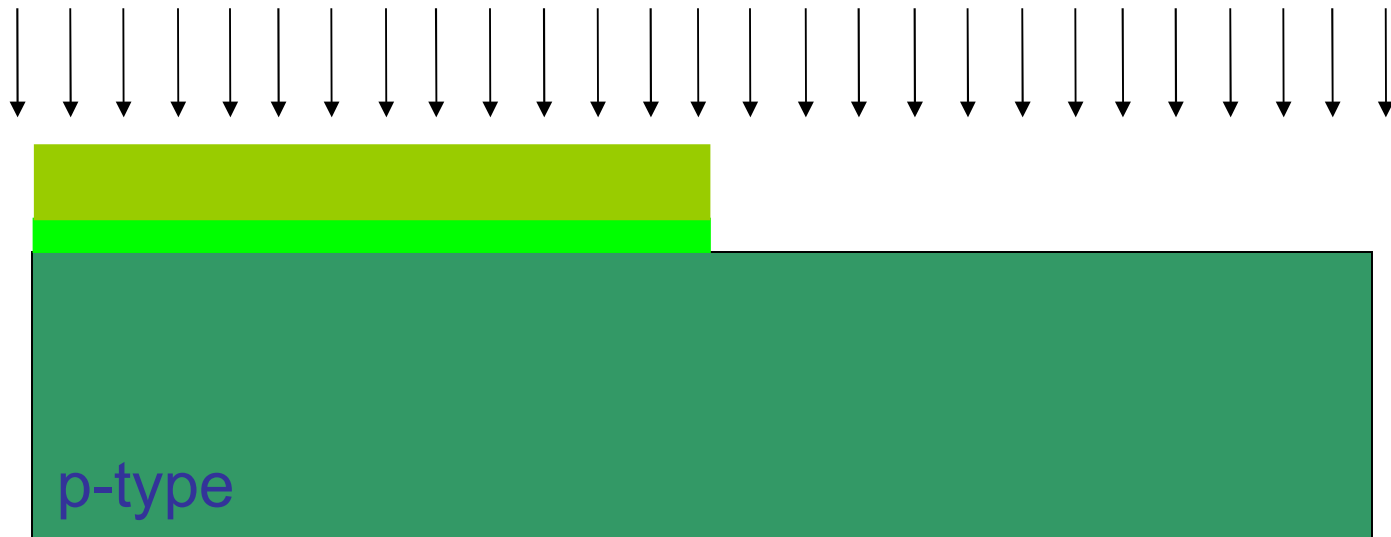
# n-well

Dry etch oxide



# n-well

n-well implantation : Phosphorus  
( $3 \times 10^{15}$  cm<sup>-2</sup> , 100 keV)





Resist strip



p-type

# n-well

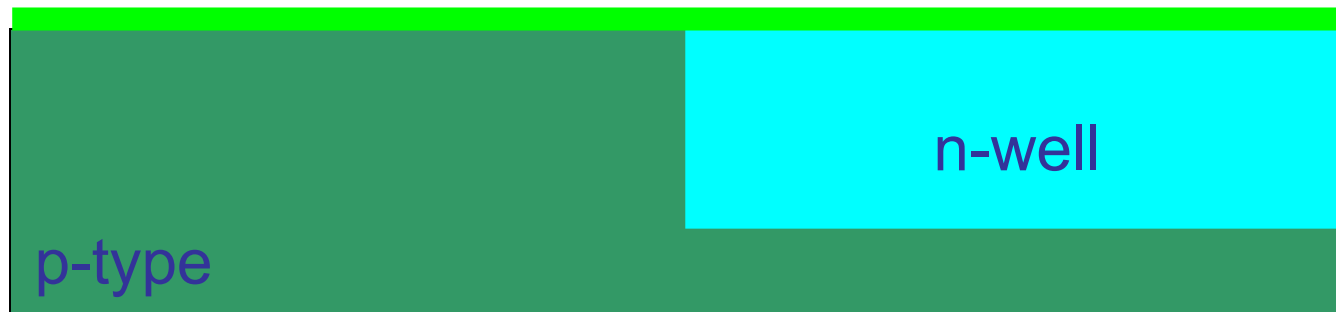
n-well drive : Anneal : N  
Differential Oxidation : O /H  
Anneal : N



## p-type Silicon Substrate

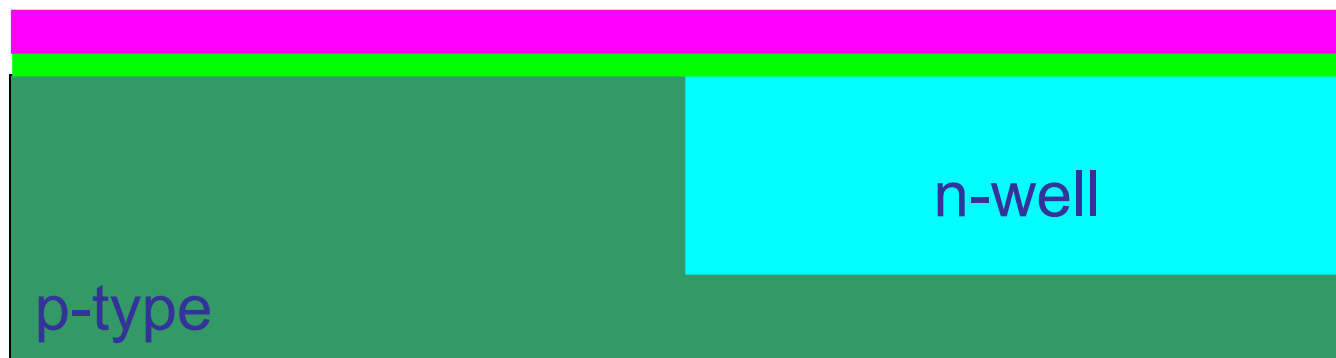
1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

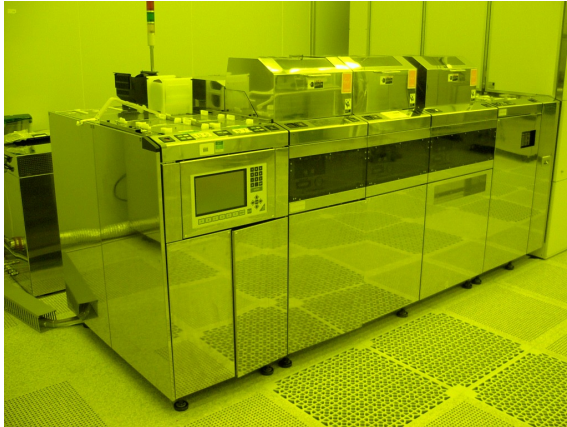
Wet etch all oxide + Pad  
oxidation (20 nm)



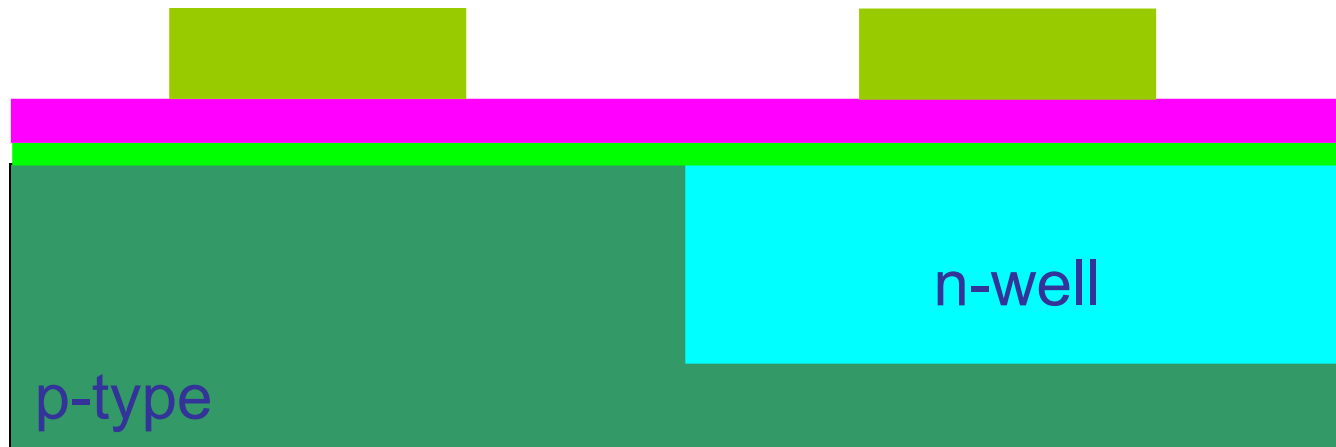


Deposition : Nitride (150 nm)

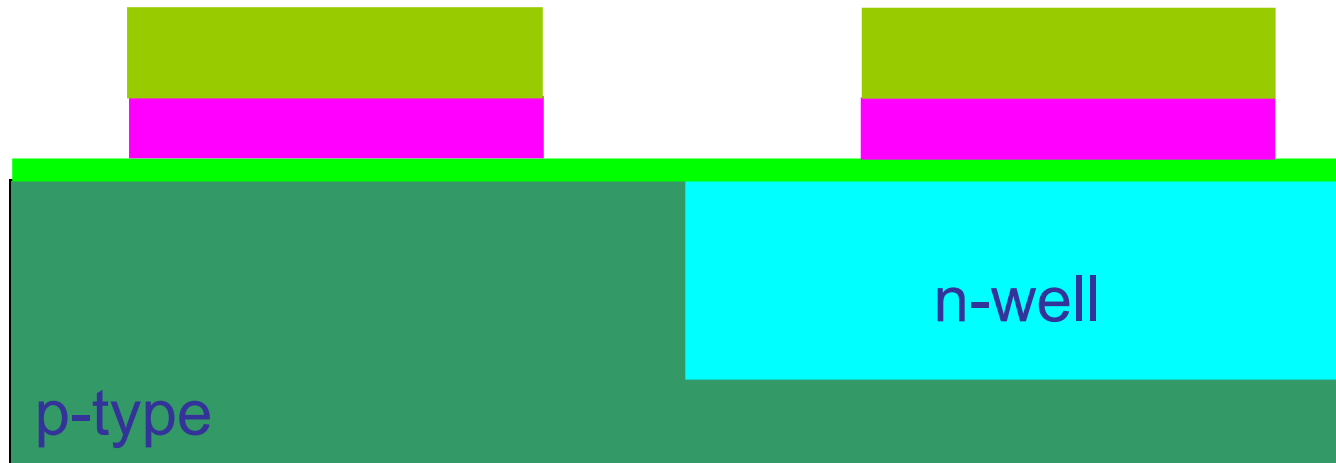
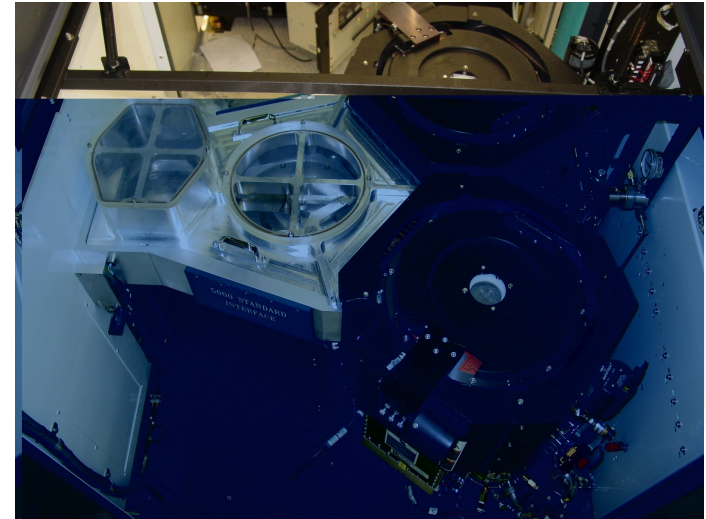




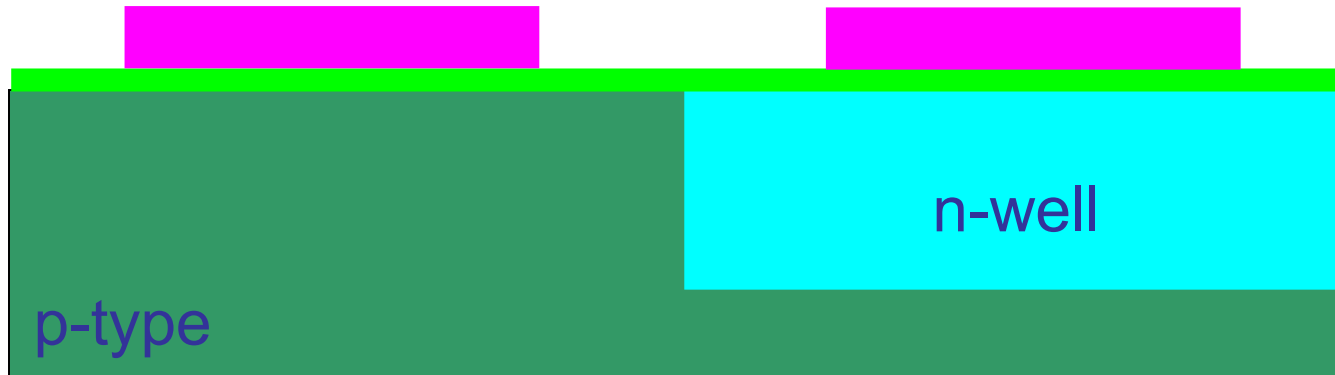
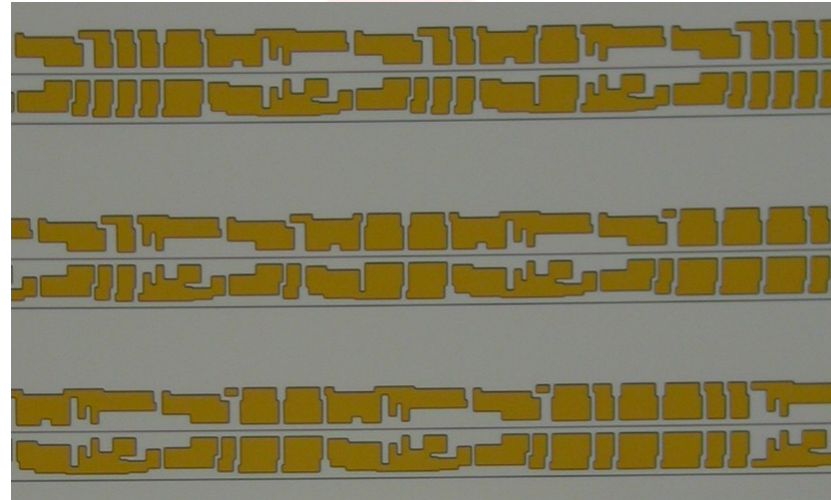
## Photolithography : ACTIVE



## Dry etch nitride

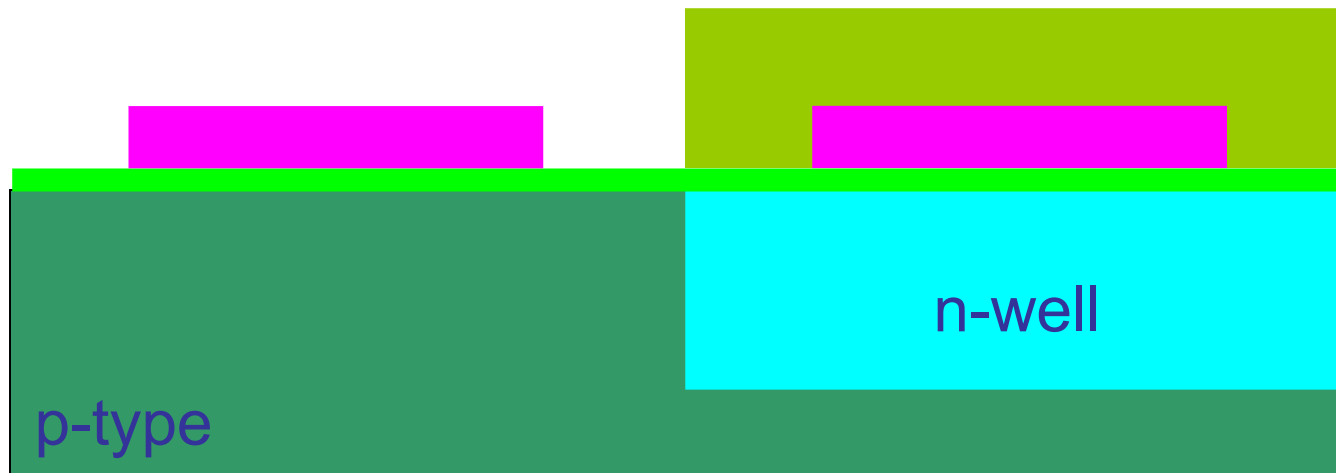


Resist strip



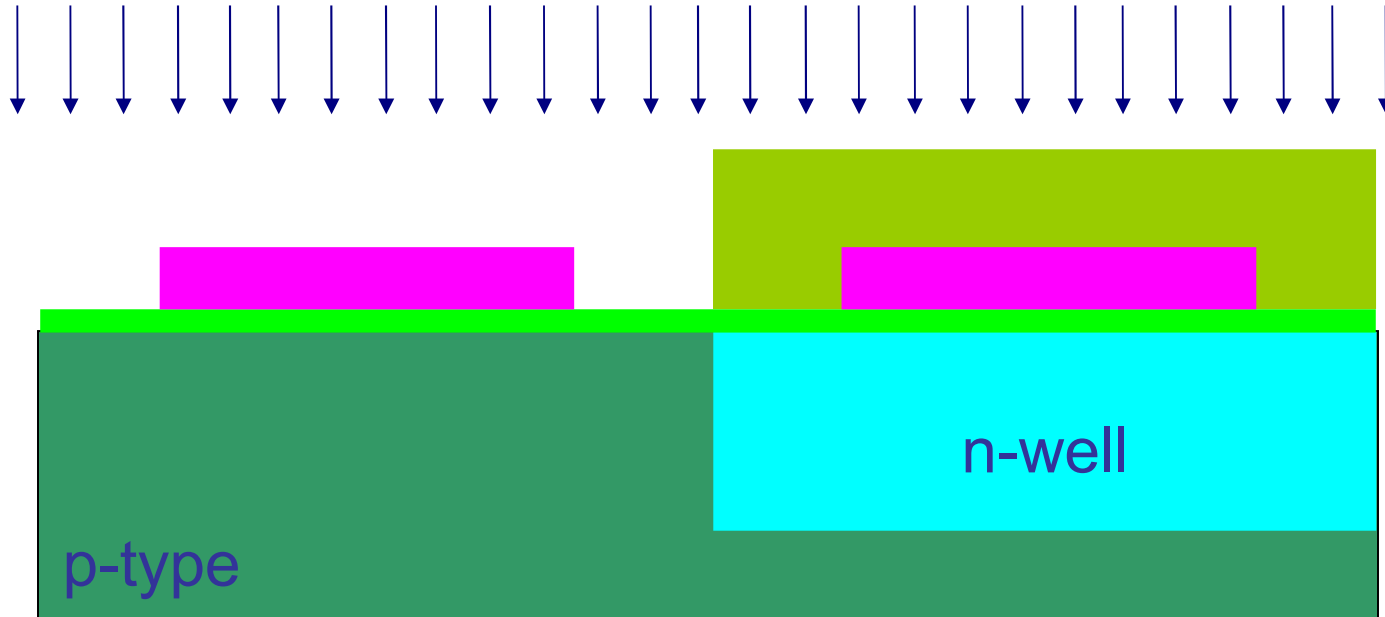


## Photolithography : NFIELD





NField implantation : Boron ( $8 \times 10^{15}$  cm<sup>-2</sup>, 60 keV)





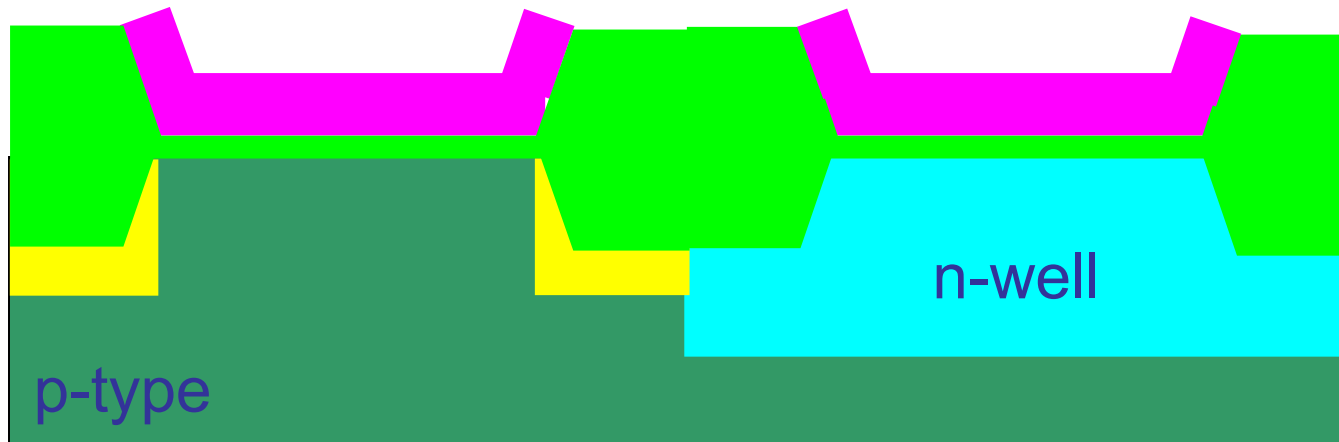
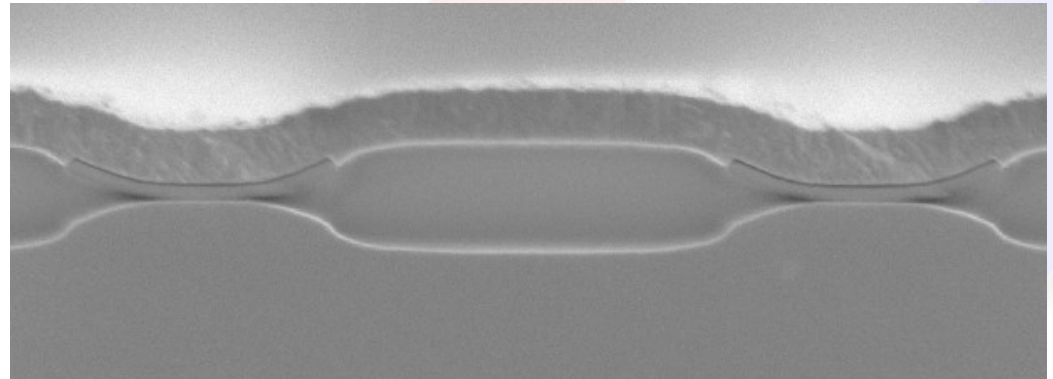


Resist strip

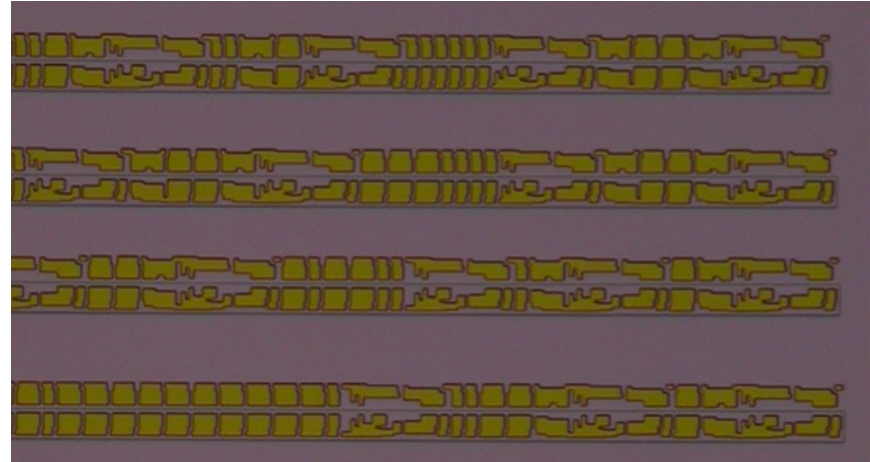




Field oxidation : O /H



## Wet etch Nitride

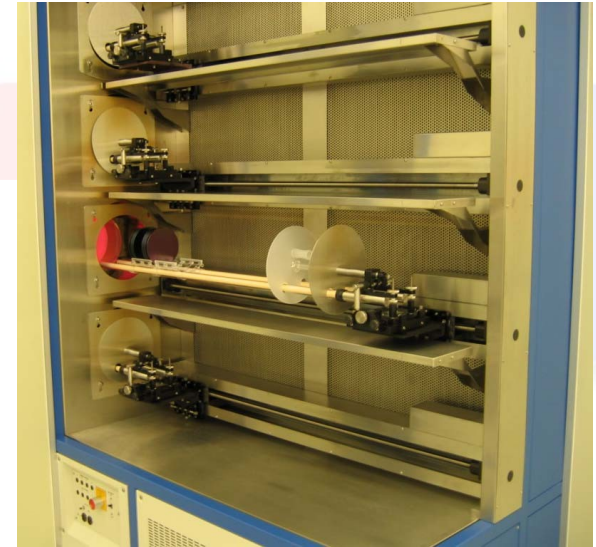


## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

# Gate

Etch Pad oxide + WR  
oxidation : H / O (50 nm)





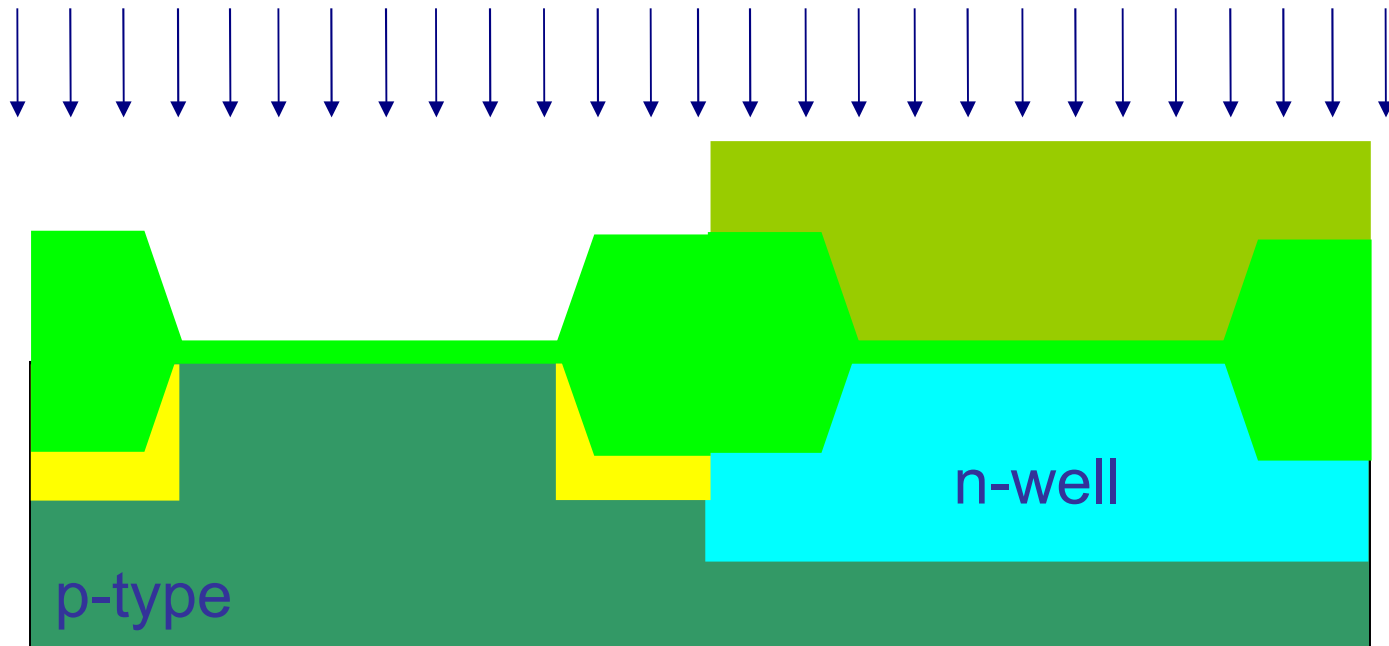
## Photolithography : NFIELD



# Gate



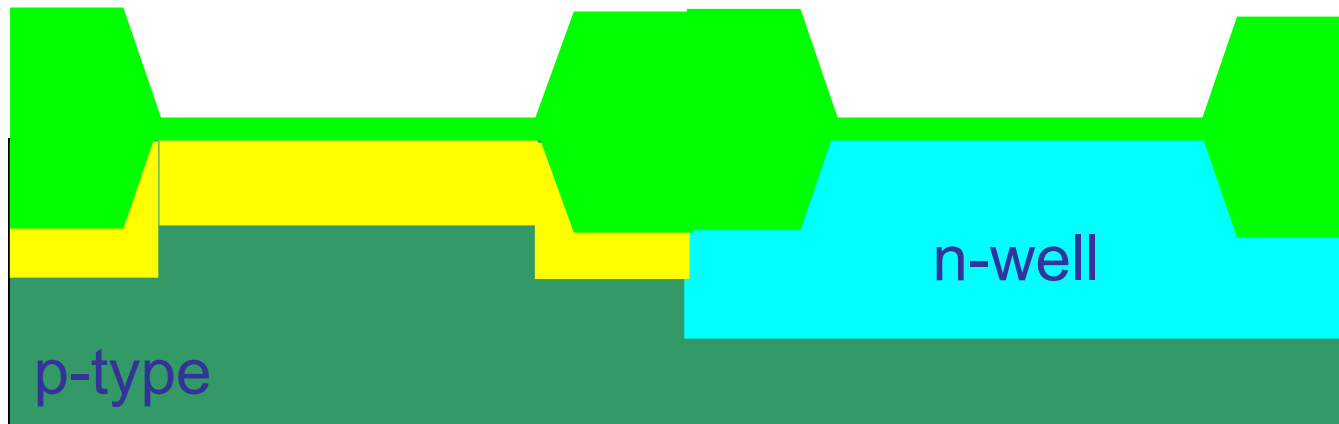
APT Implantation : Boron  
( $6.5 \times 10^{15} \text{ cm}^{-2}$  , 110 keV)



# Gate



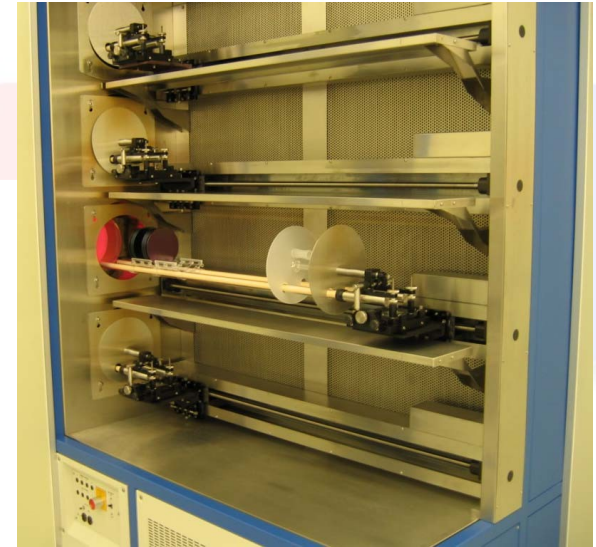
Resist strip





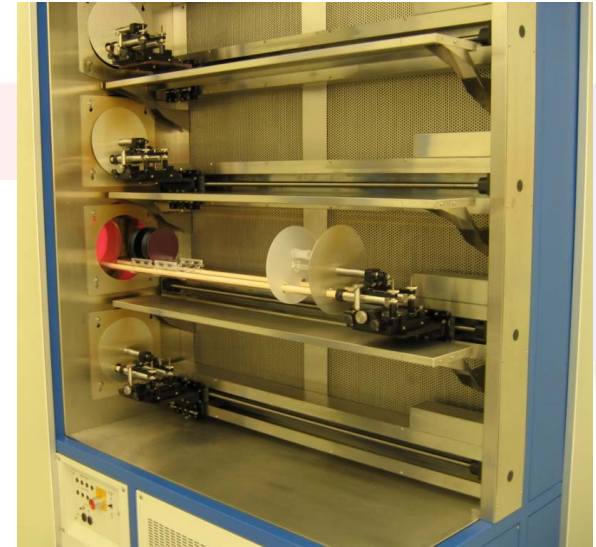
# Gate

Anneal : N



# Gate

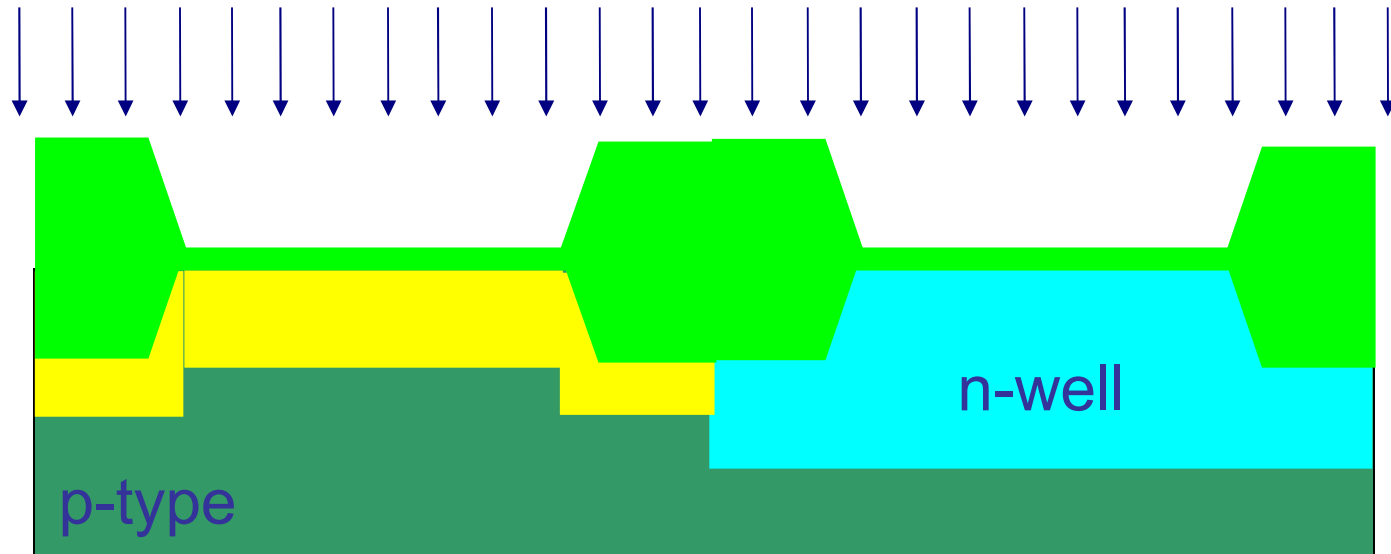
Etch WR oxide + Gate oxidation  
(25 nm)



# Gate



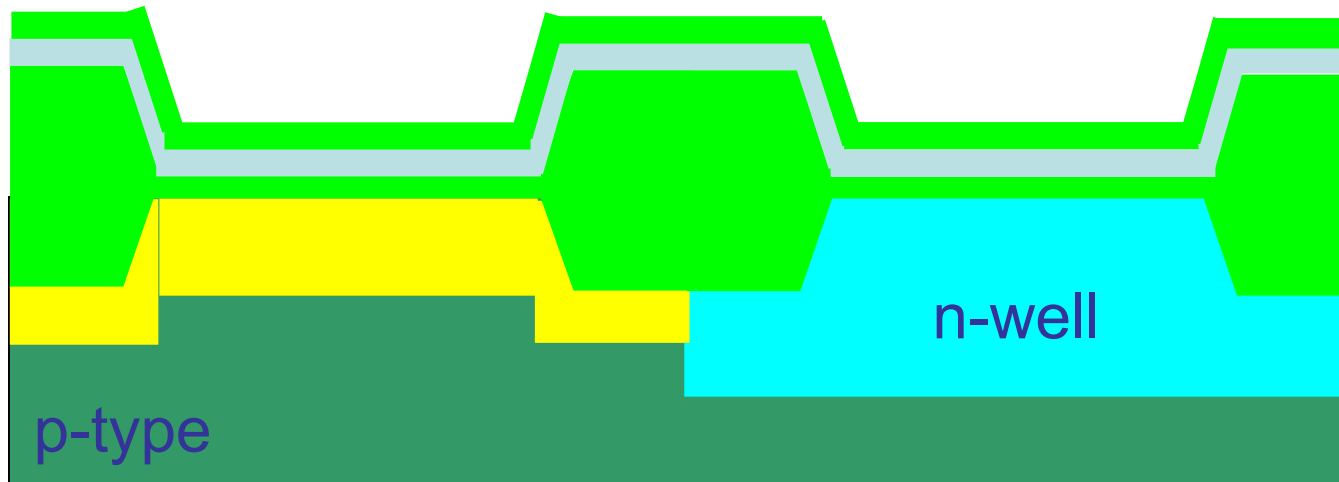
VTA implantation : Boron ( $8 \times 10^{11}$  cm<sup>-2</sup>, 20 keV)



## Poly deposition



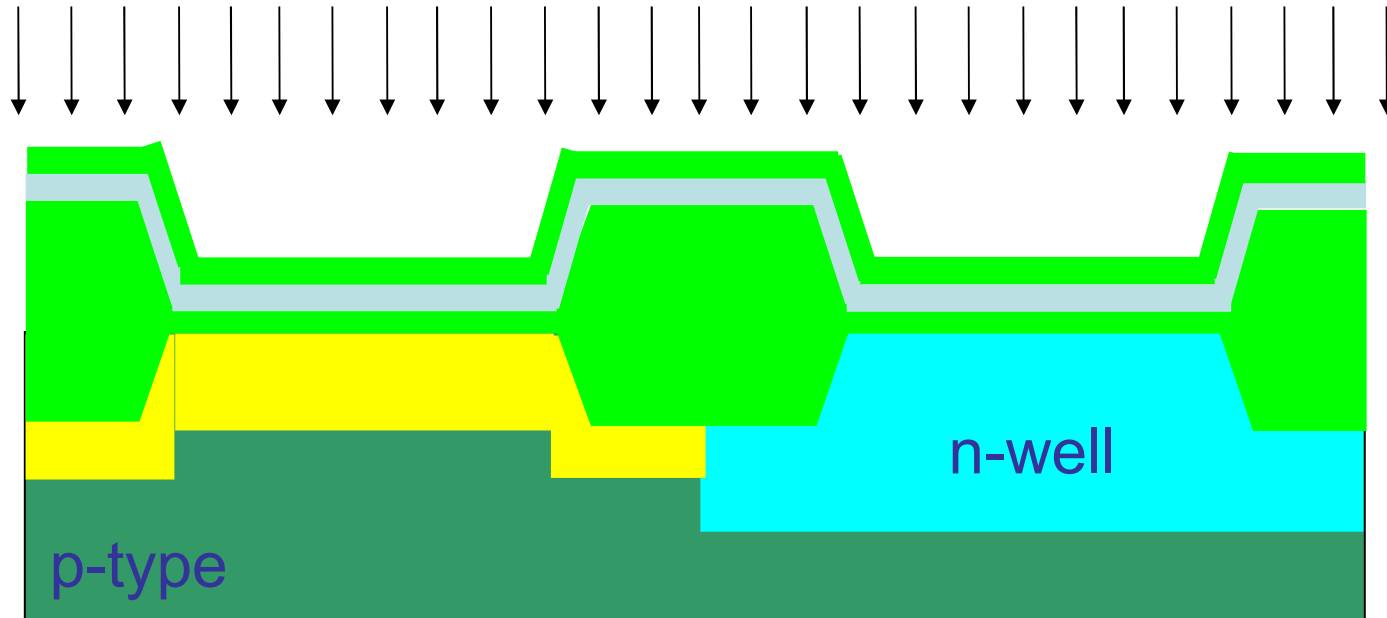
TEOS deposition



# Gate

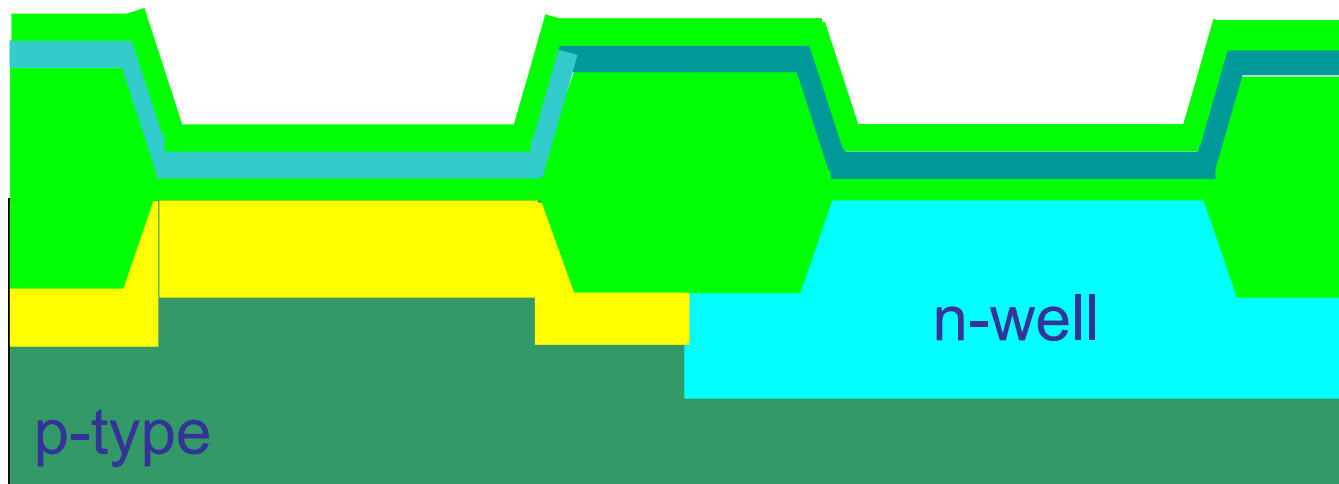
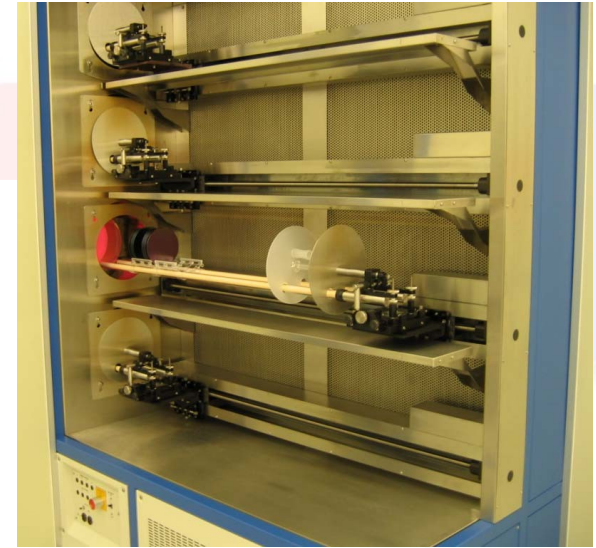


Poly implantation : Phosphorus  
( $1.2 \times 10^{18}$  cm<sup>-3</sup>, 50 keV)





Anneal : N







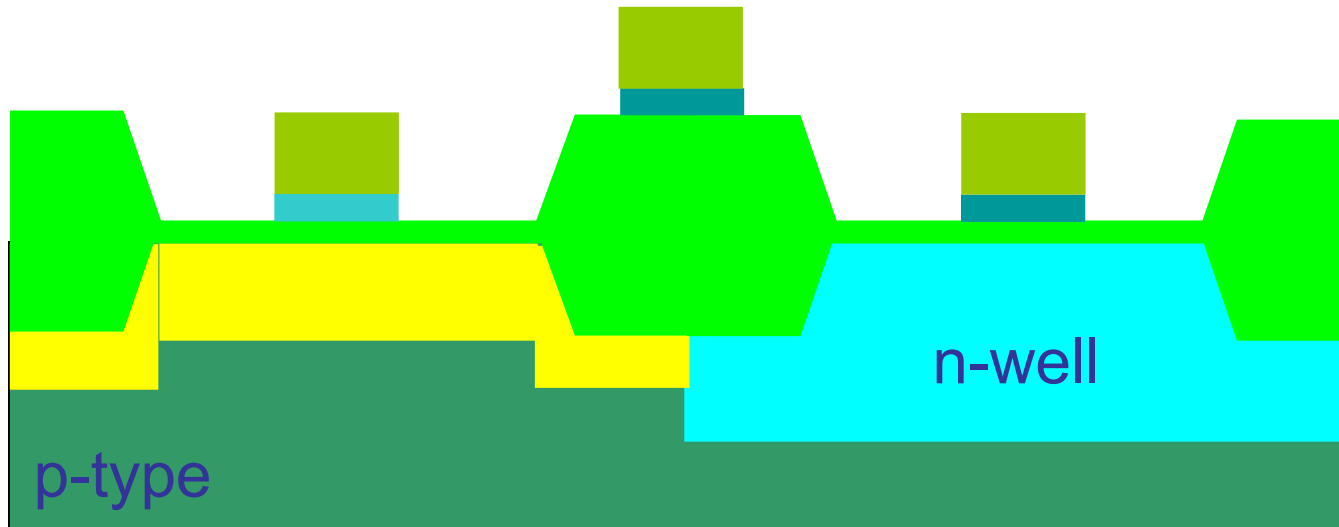
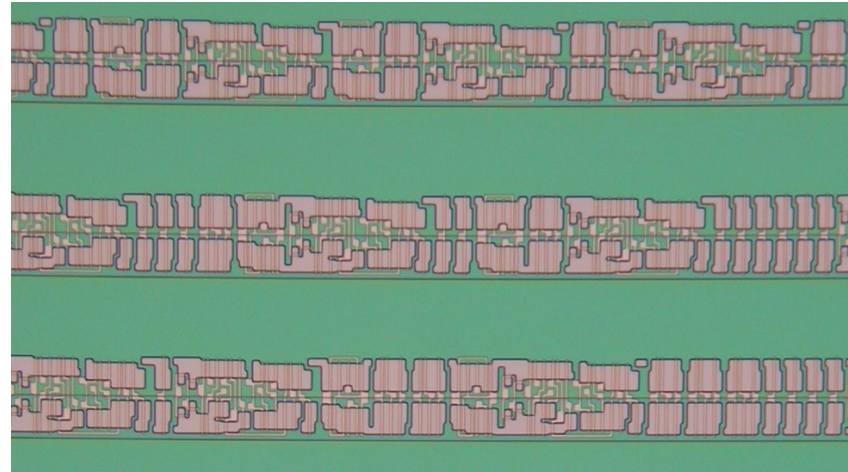
## Wet etch TEOS





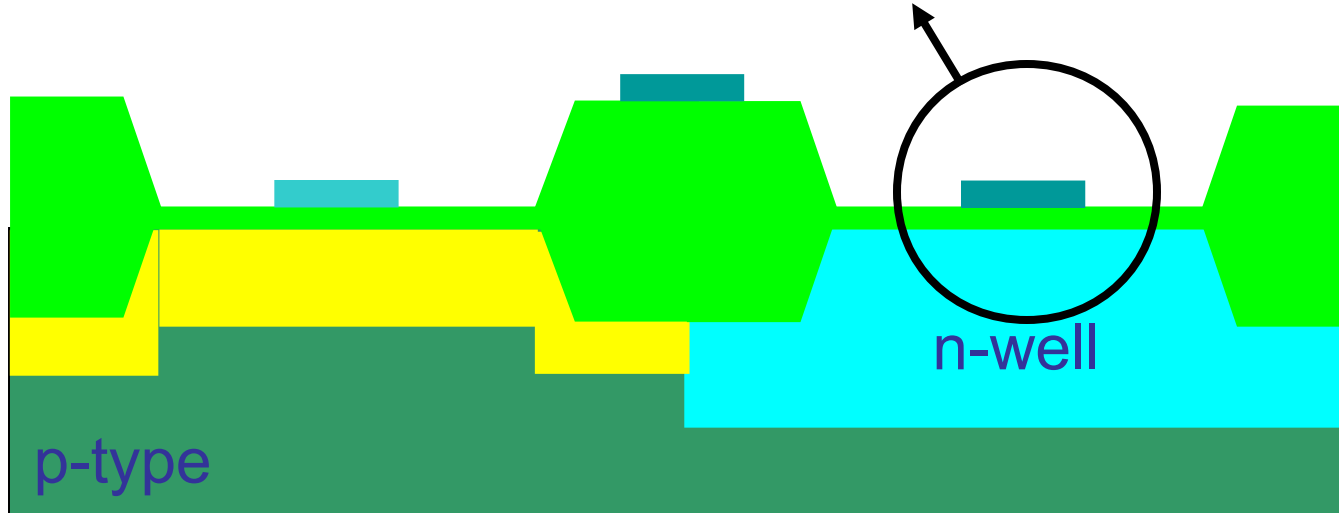
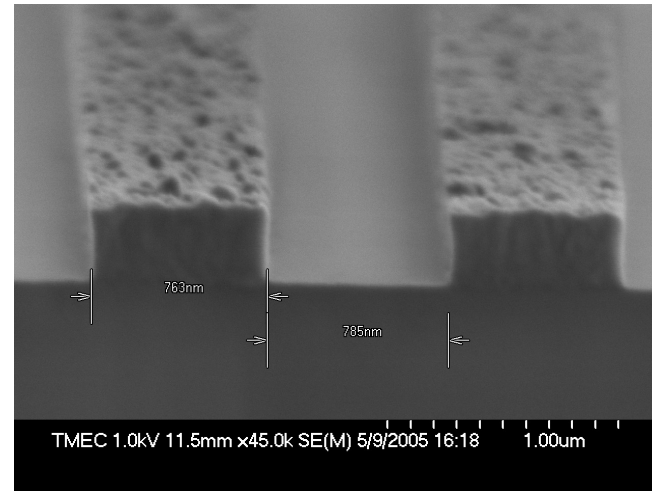
# Gate

Dry etch poly



# Gate

Resist strip

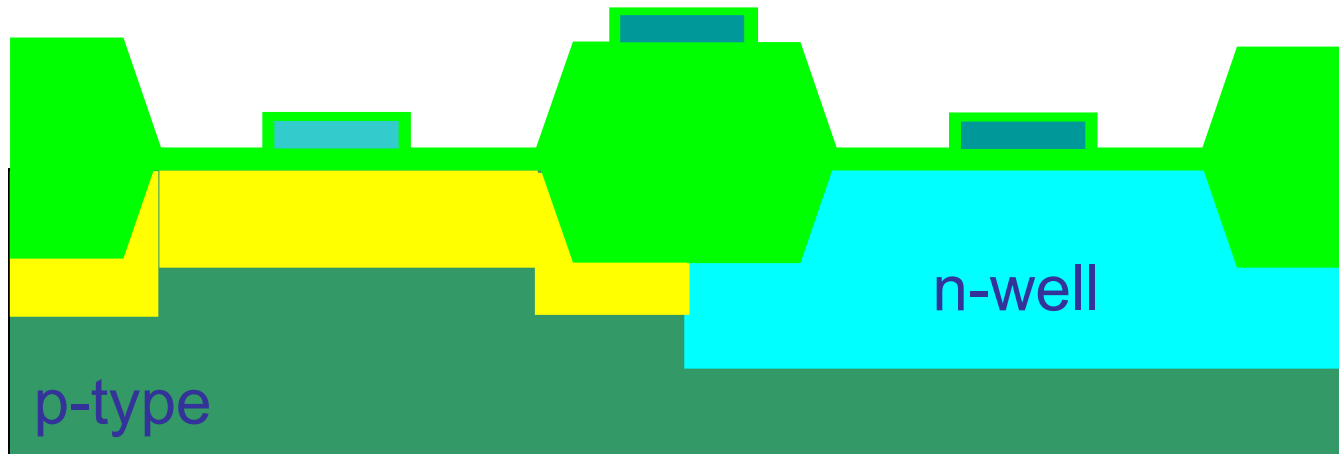
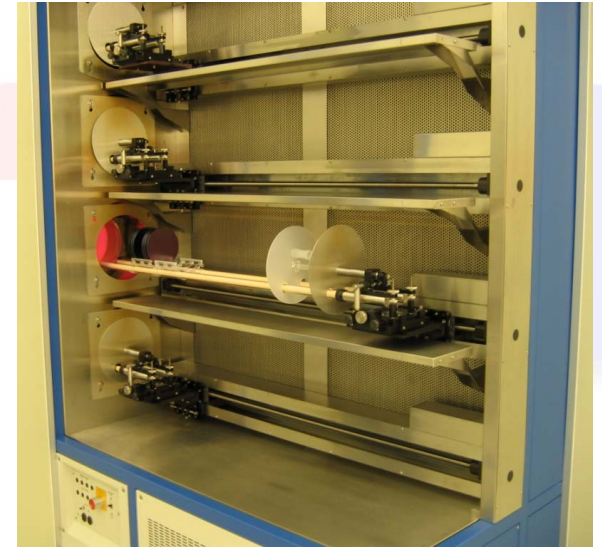


## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

# Junctions

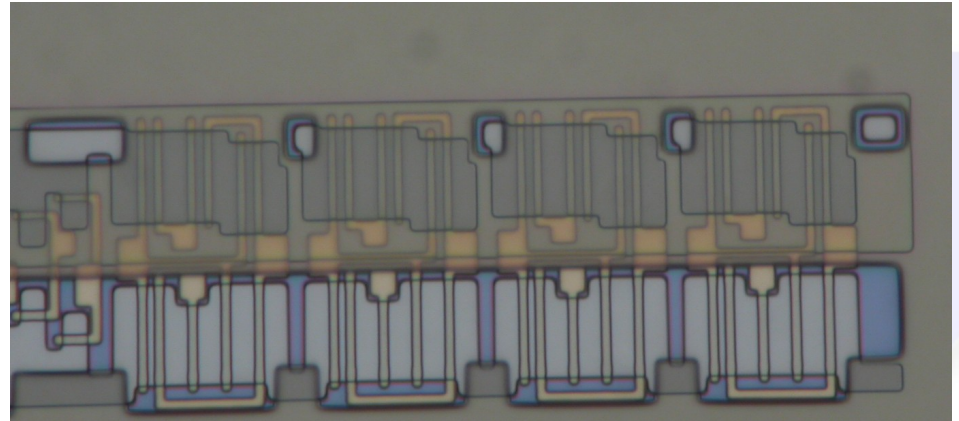
Oxidation : O





# Junctions

Photolithography : NPLUS

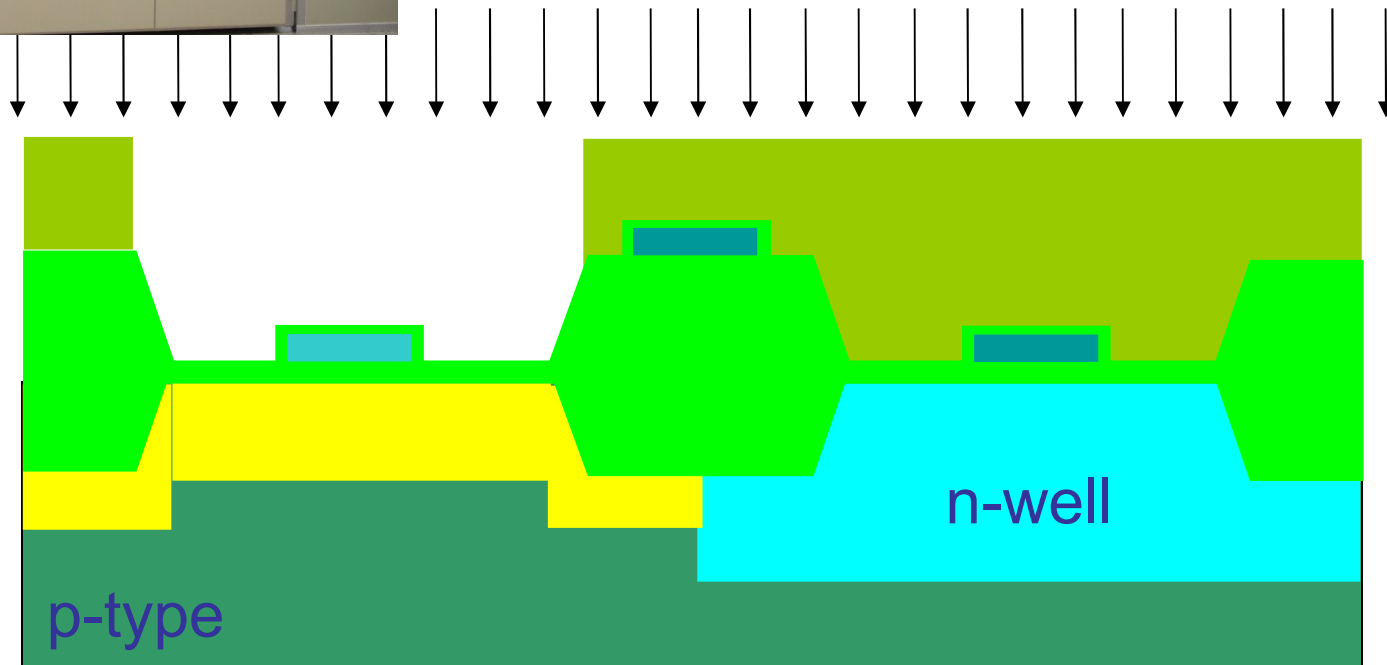




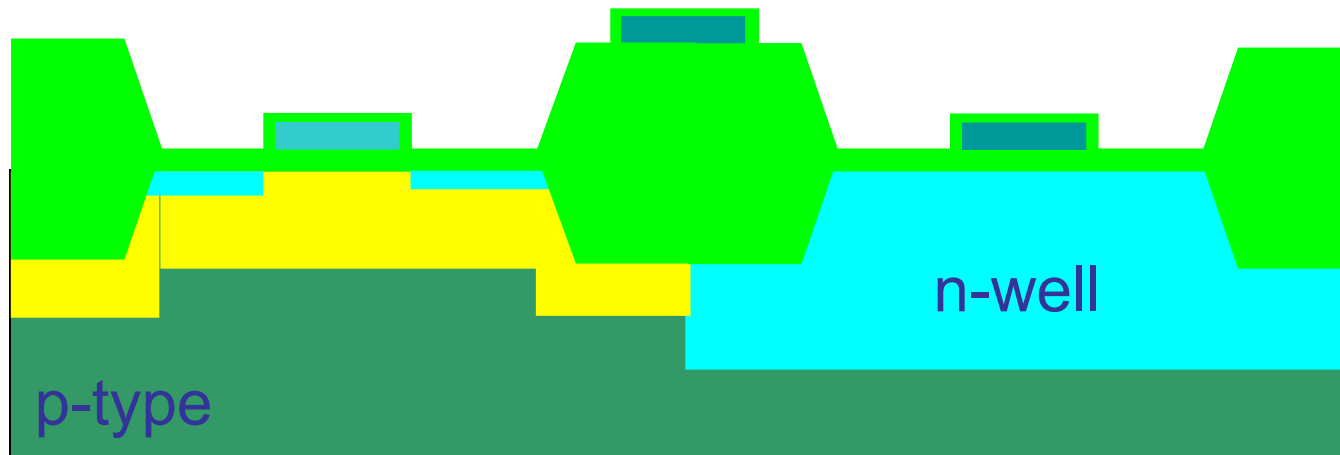
# Junctions



Nplus implantation :  
Phosphorus ( $10^{15}$  cm<sup>-3</sup> , 70 keV)  
Arsenic ( $6 \times 10^{15}$  cm<sup>-3</sup> , 130 keV)

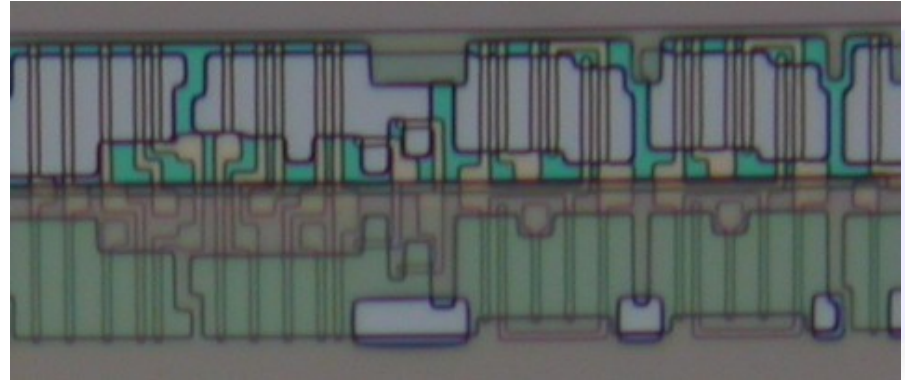


Resist strip



# Junctions

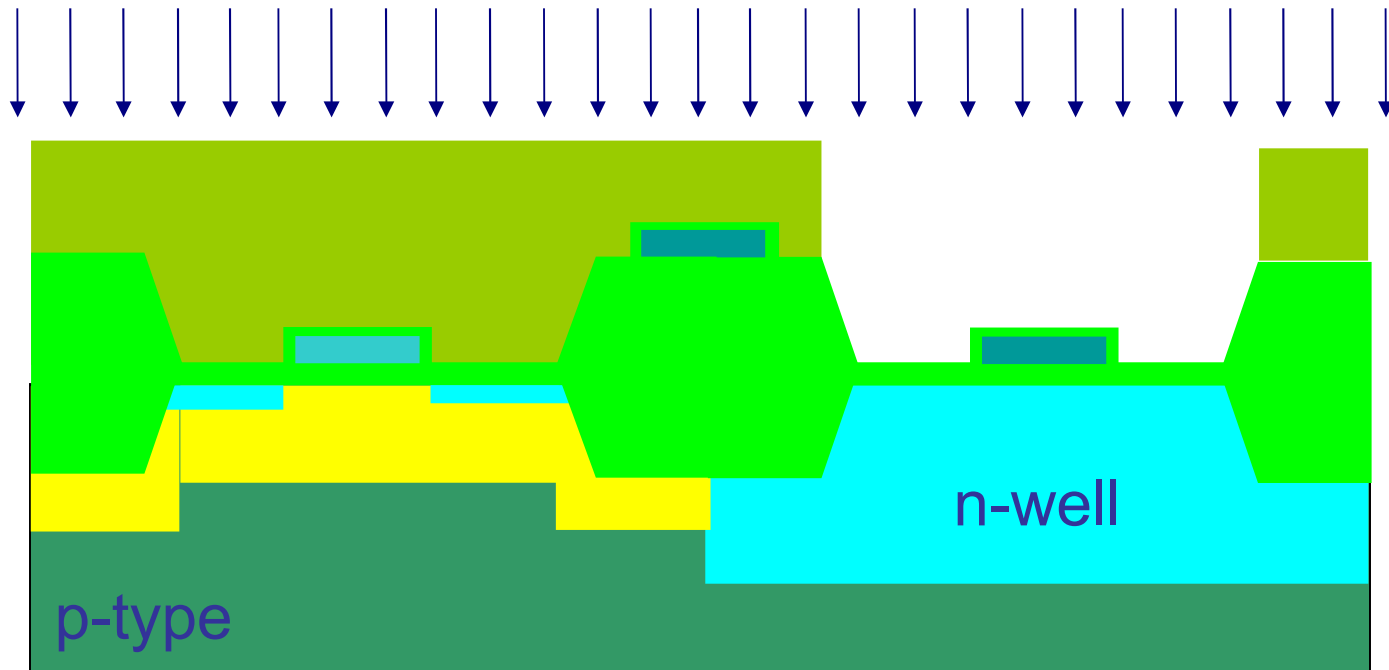
Photolithography : PPLUS



# Junctions



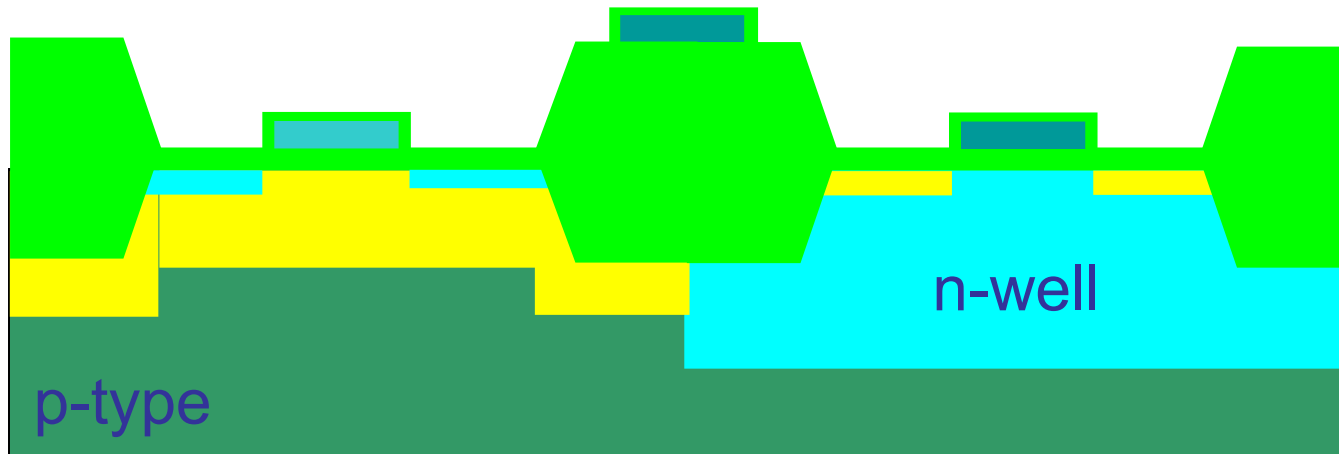
Pplus implantation :  
Boron ( $5 \times 10^{15} \text{ cm}^{-2}$ , 20 keV)



# Junctions



Resist strip



# Junctions



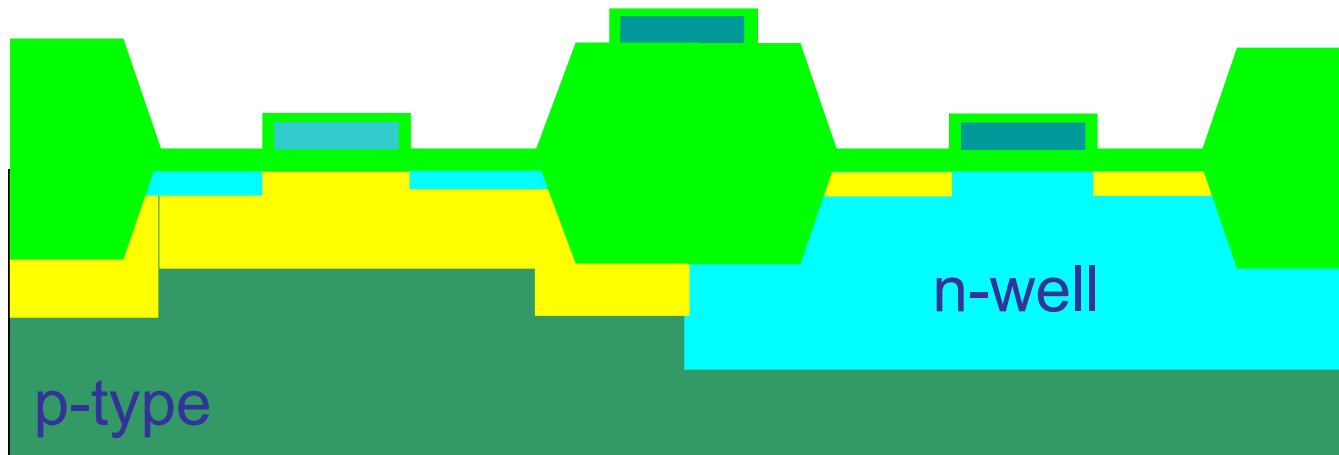
Coat front + Backside etch



# Junctions

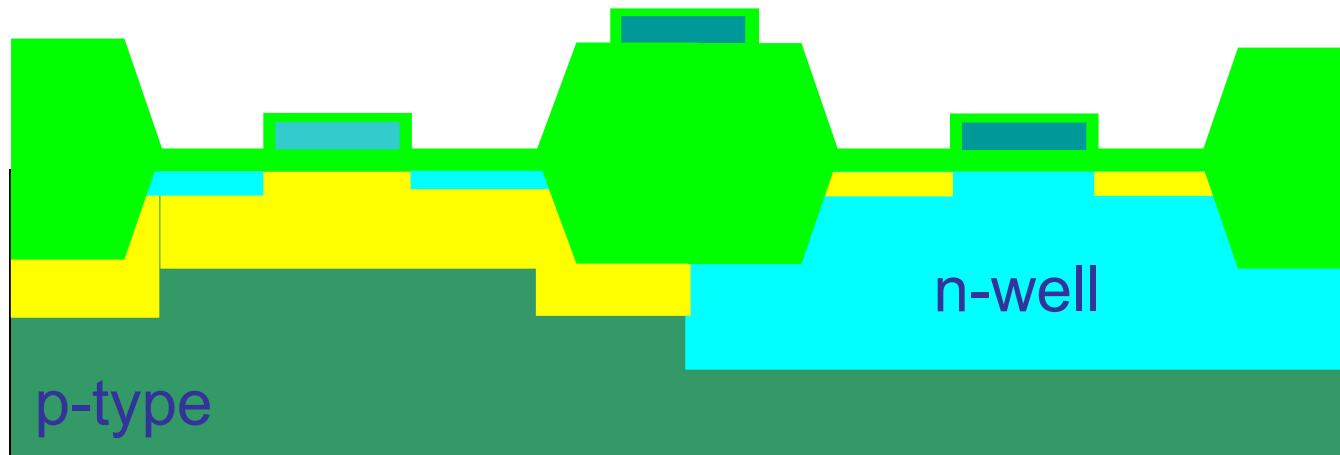


Resist strip





Rapid thermal anneal : N

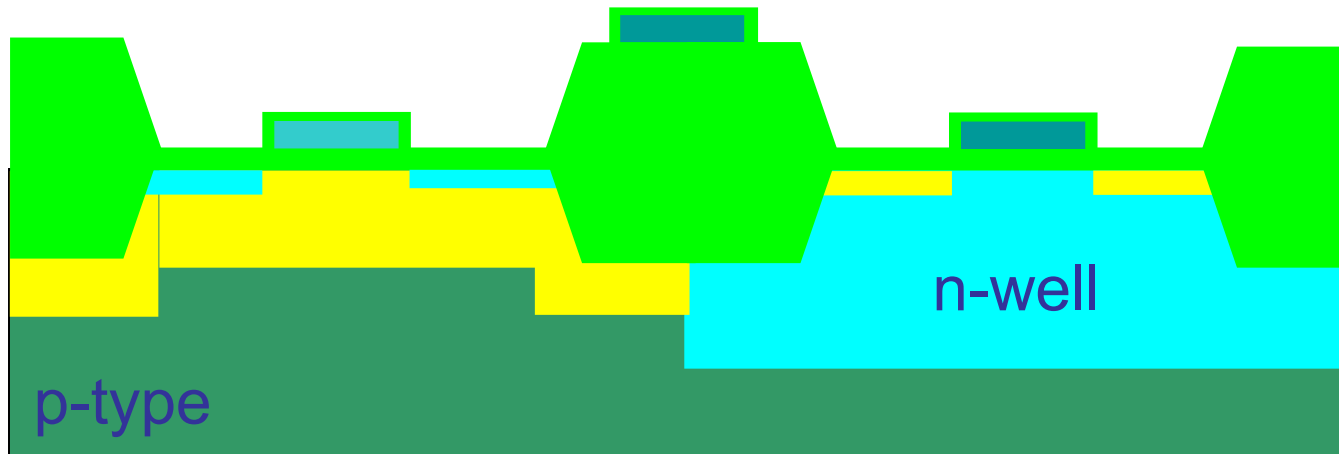


## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. Interlayer Dielectric (ILD)
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

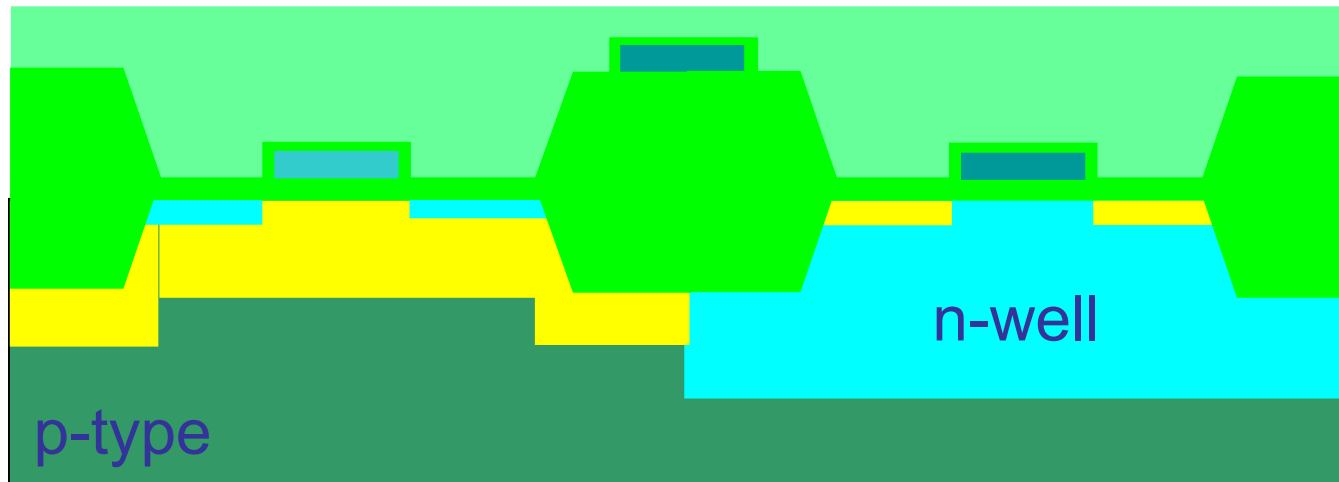
# Interlayer Dielectric

TEOS deposition : UTEOS



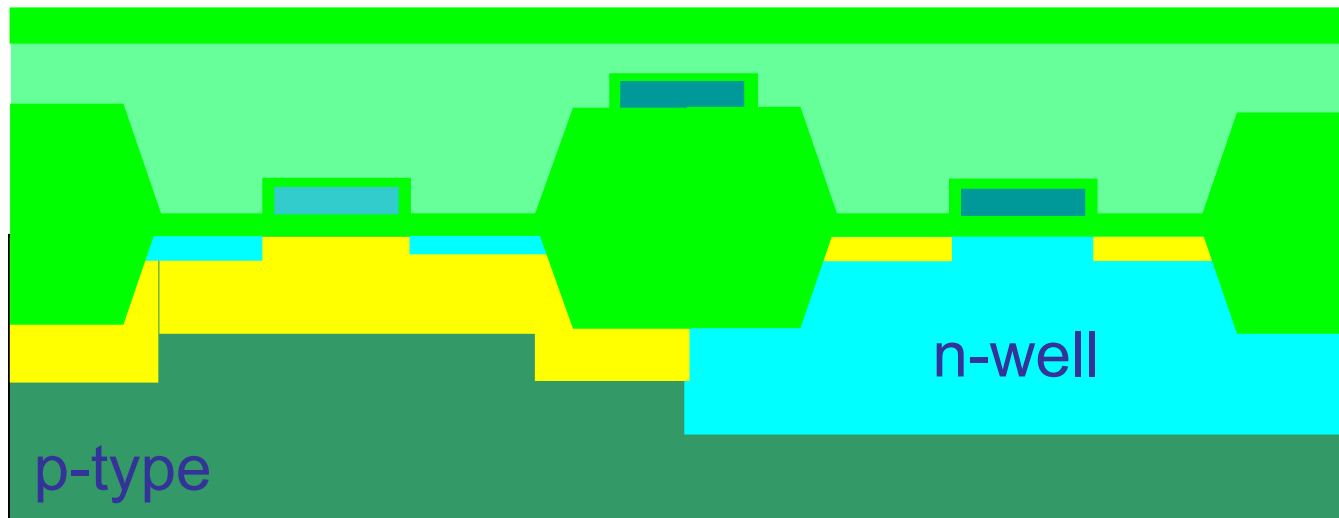
# Interlayer Dielectric

SOG coat  
SOG cure  
SOG coat  
SOG Cure



# Interlayer Dielectric

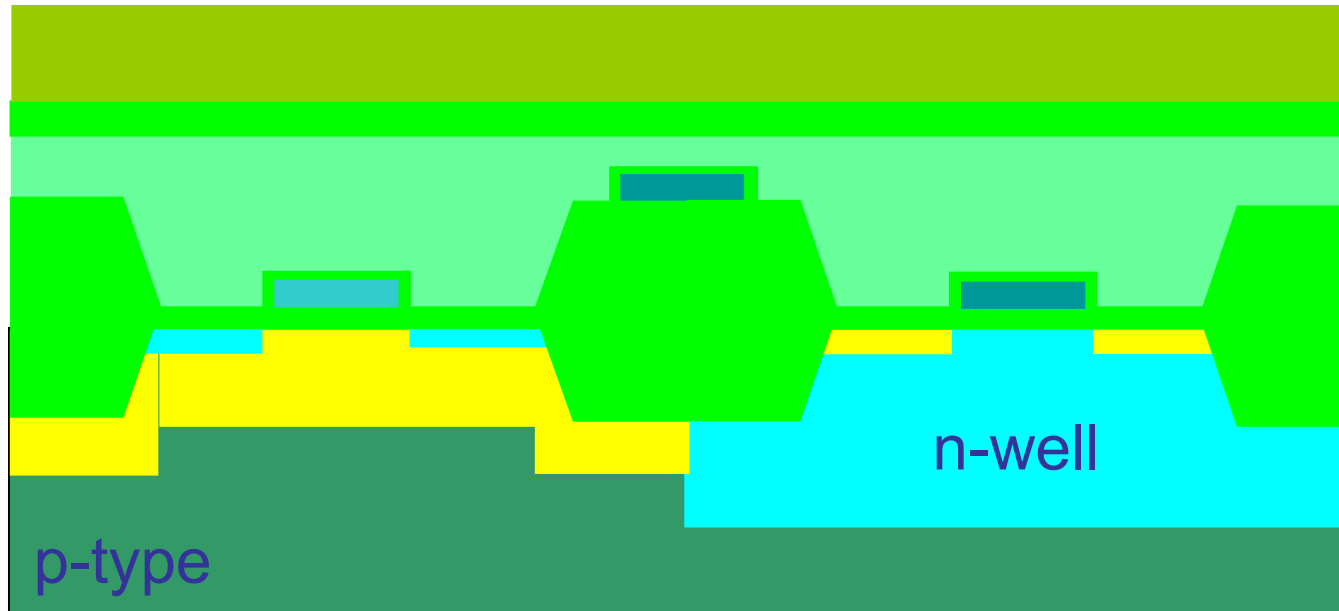
PSG deposition  
PSG densification



# Interlayer Dielectric



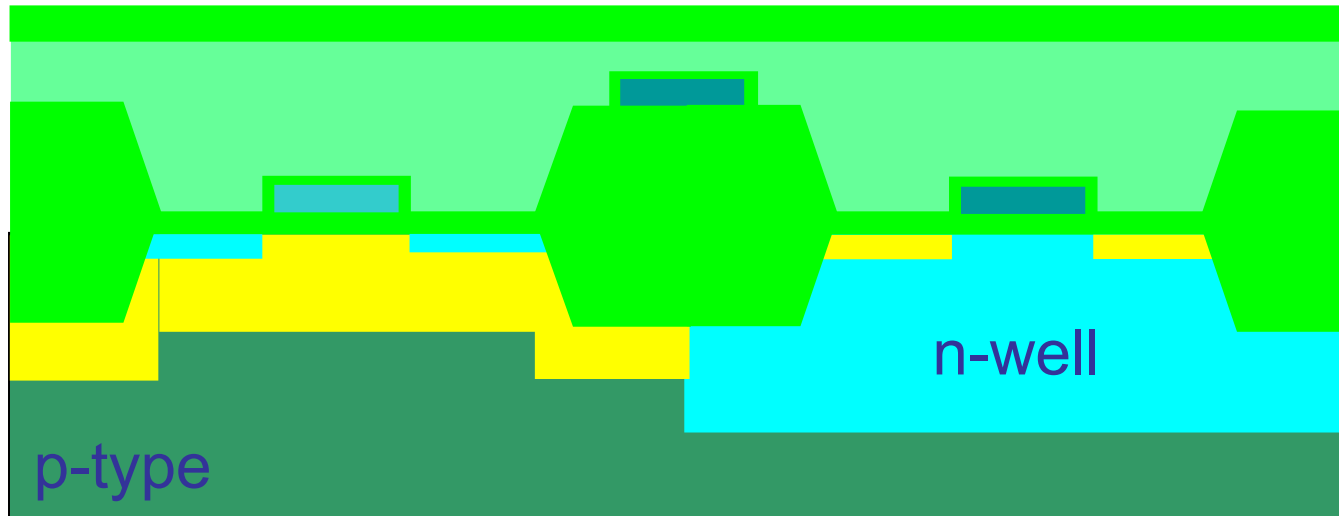
Coat front  
Backside etch



# Interlayer Dielectric



Resist strip





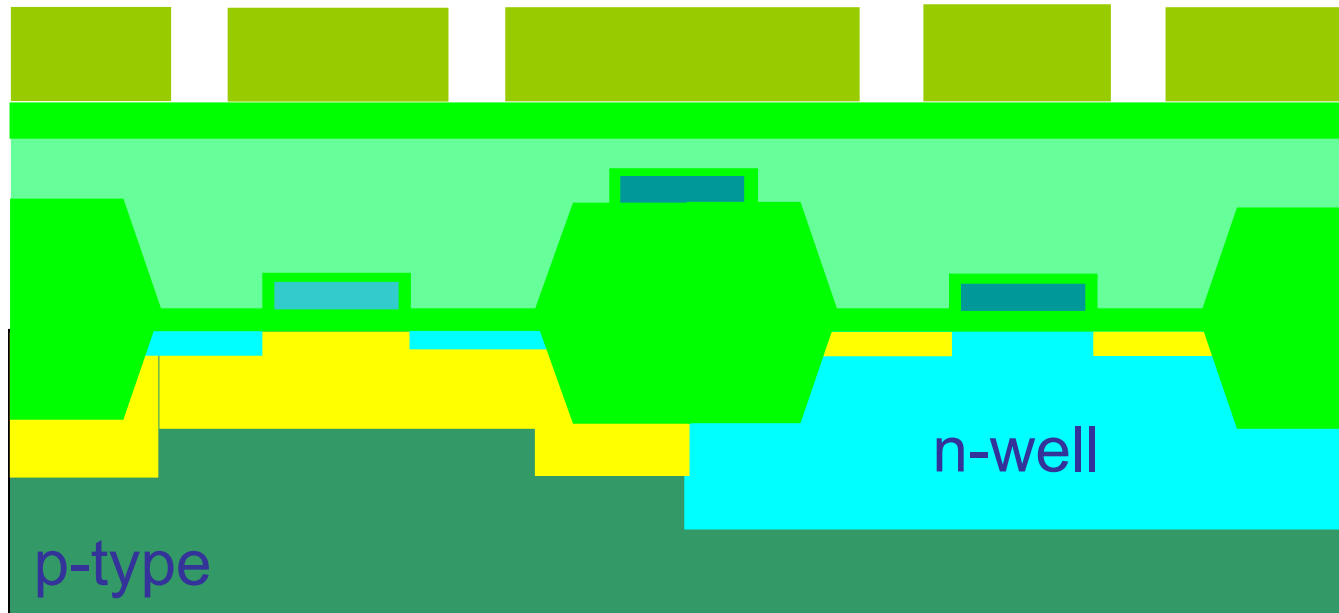
## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

# Contacts and Metal1

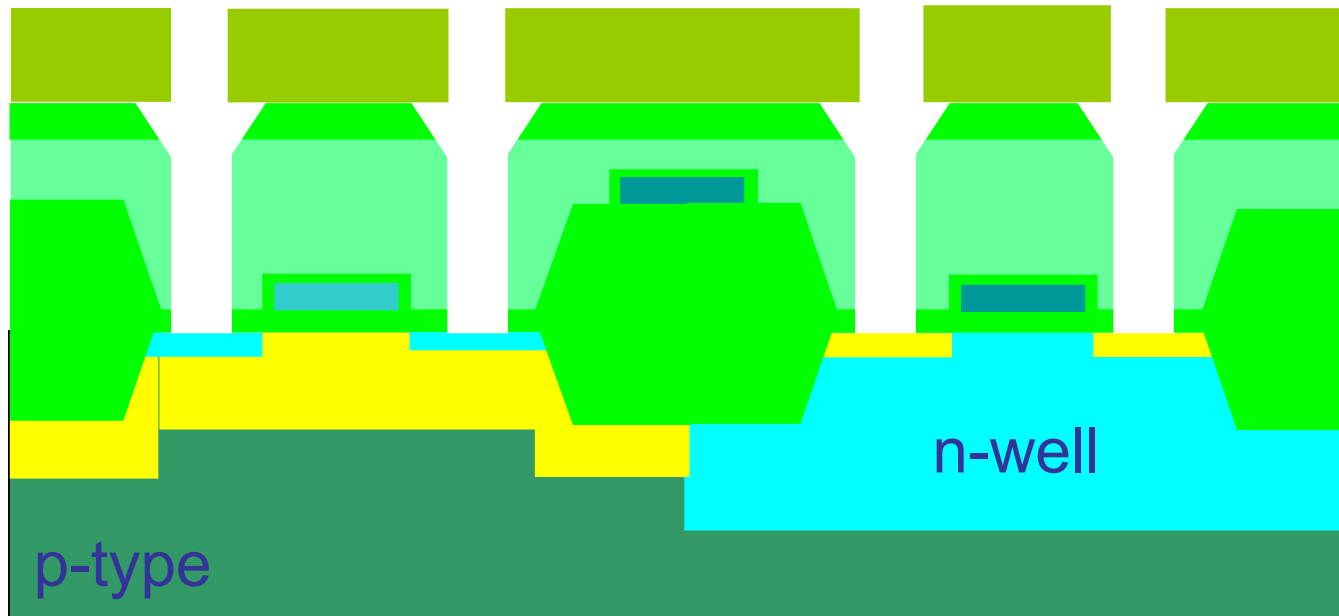
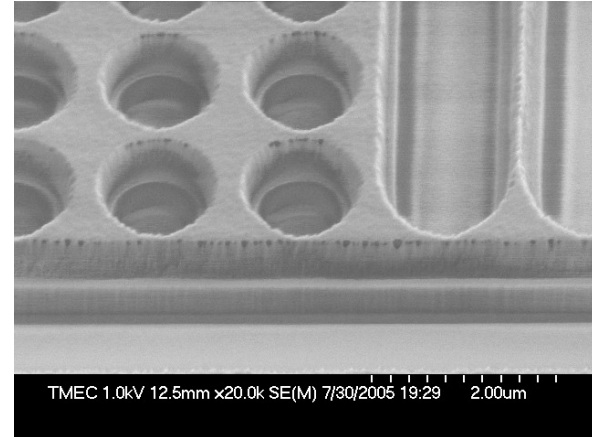


## Photolithography : CONTACT



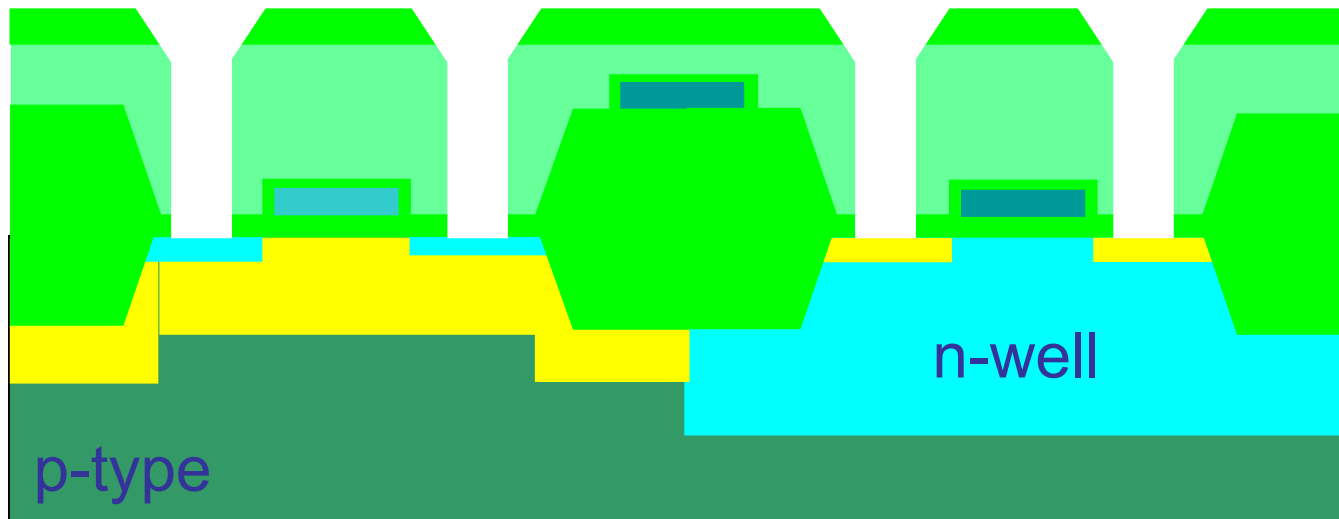
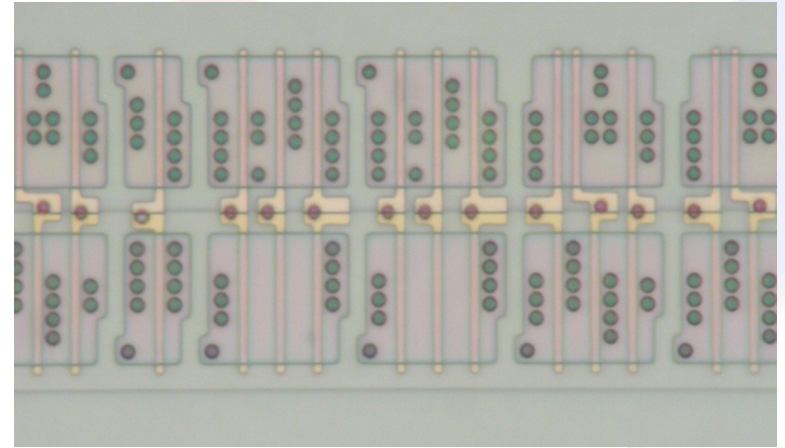
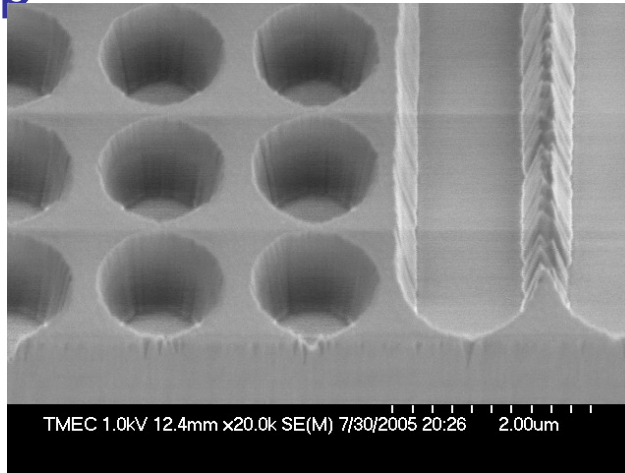
# Contacts and Metal1

Dry etch contacts :  
isotropic + anisotropic



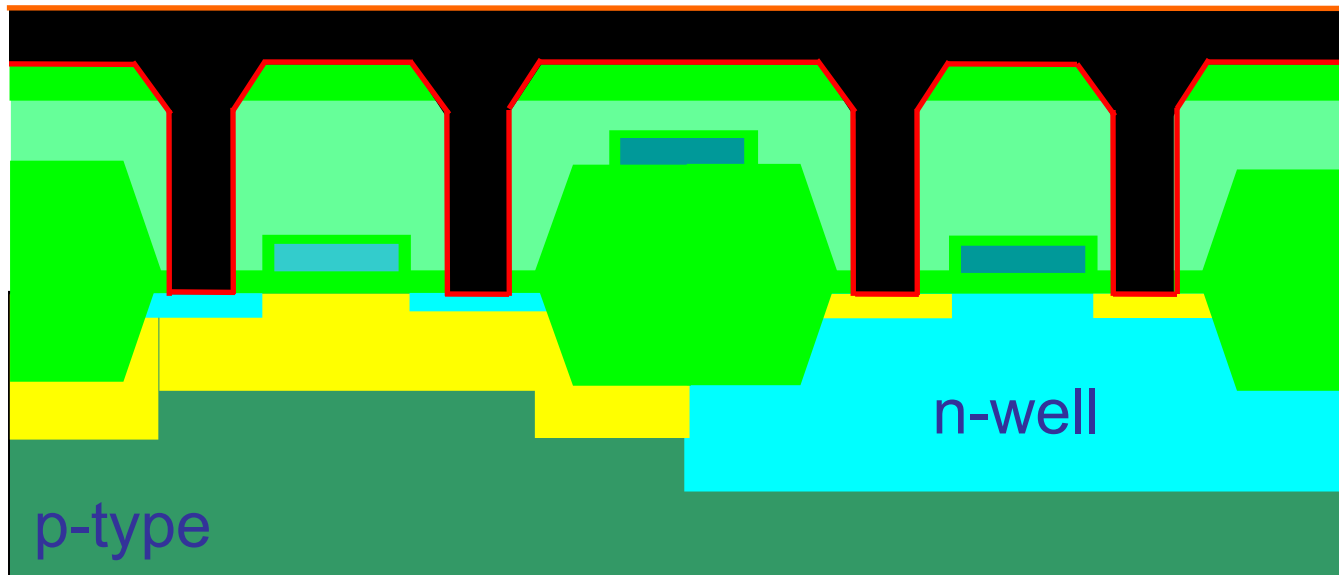
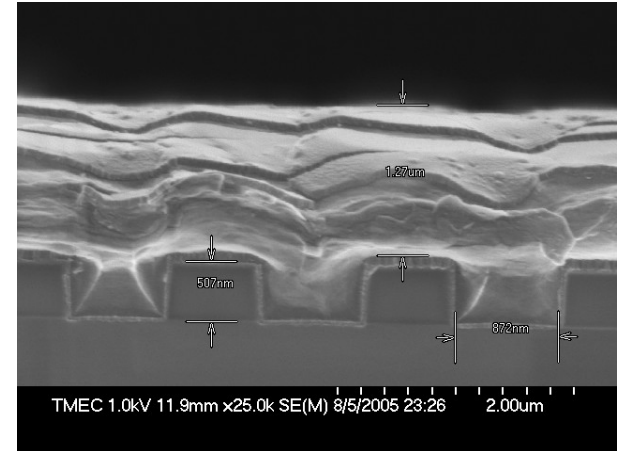
# Contacts and Metal1

## Resist strip



# Contacts and Metal1

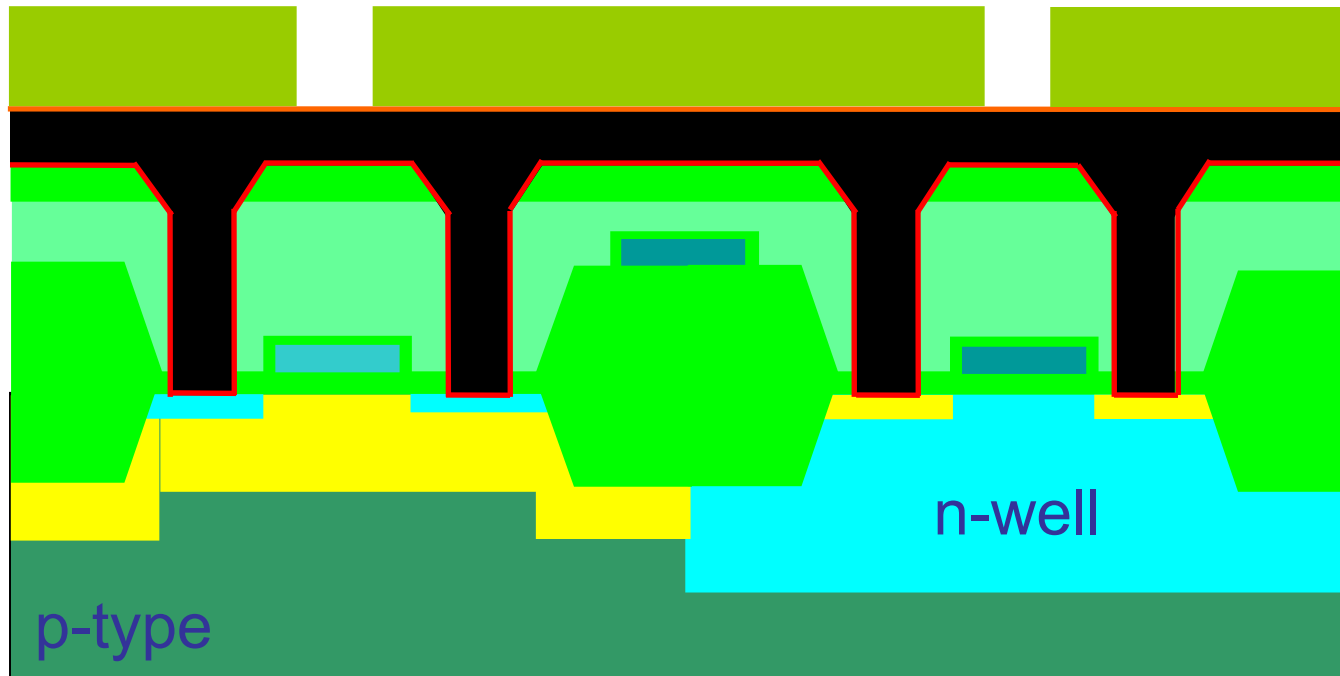
Contract clean  
Metal 1 sputtering : TiTiN  
AlSiCu  
TiN



# Contacts and Metal1

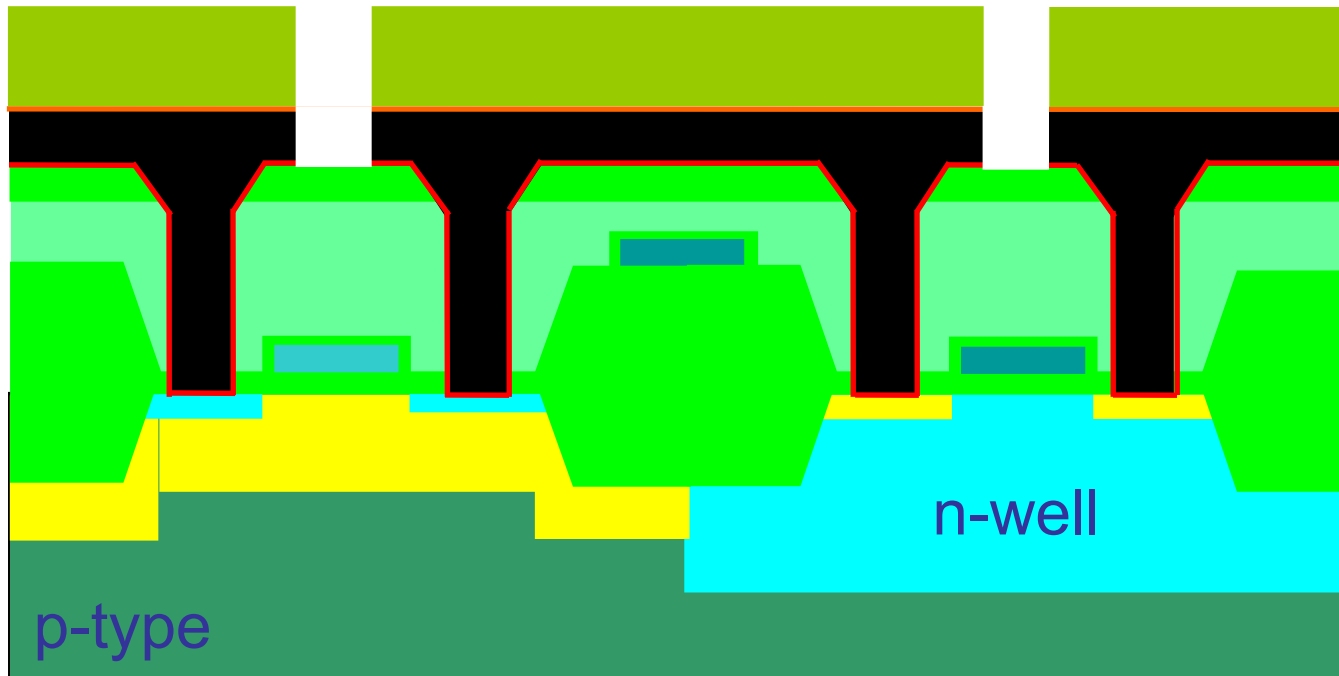
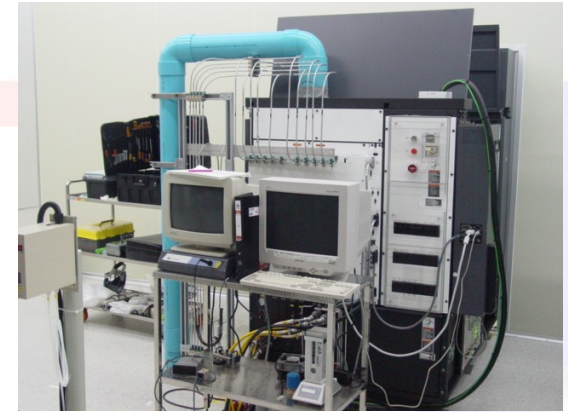


## Photolithography : METAL1



# Contacts and Metal1

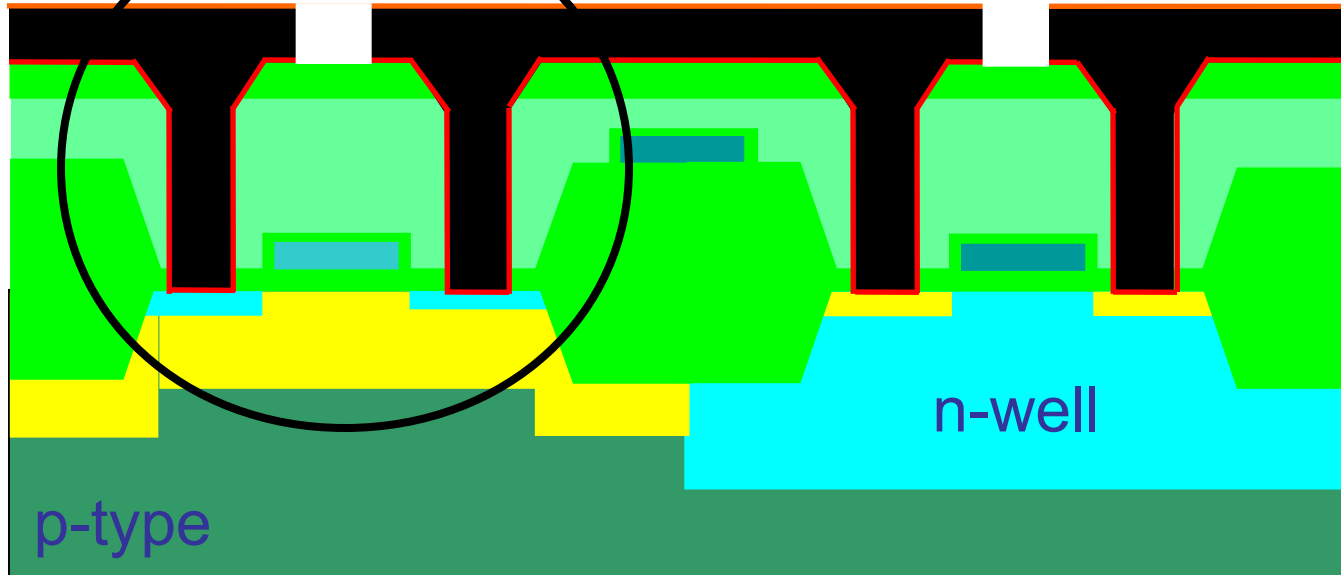
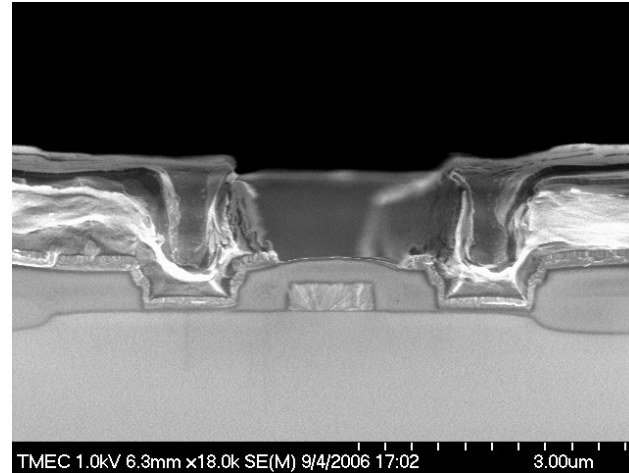
Dry etch Metal 1





# Contacts and Metal1

Resist strip

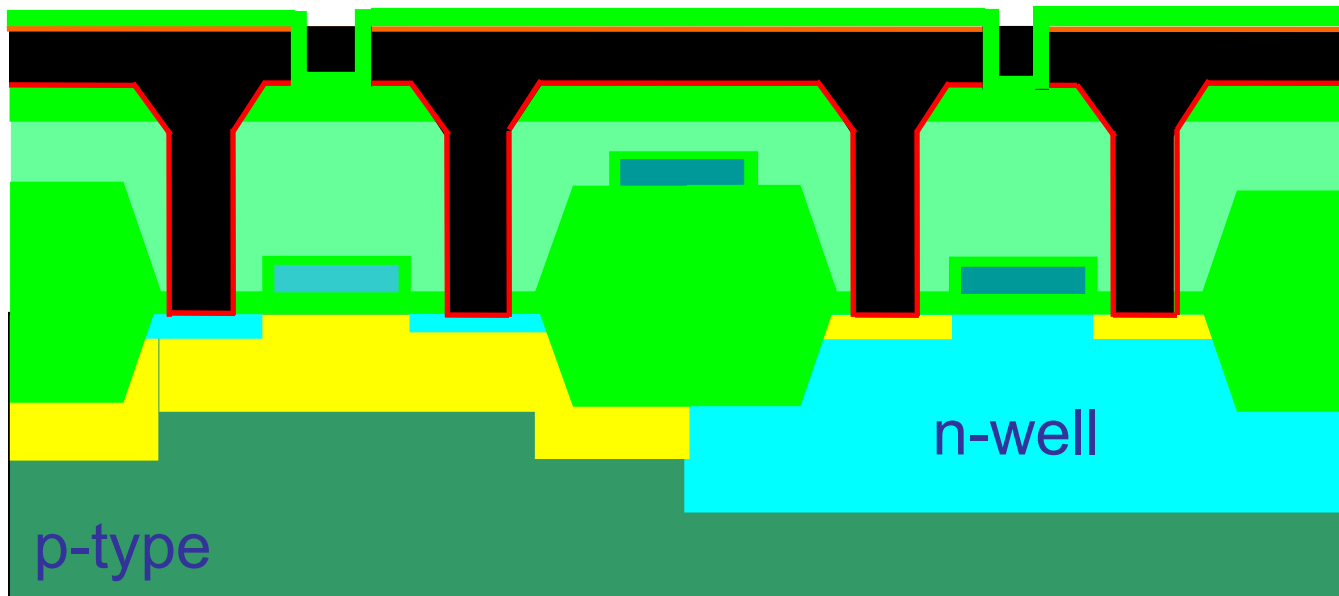
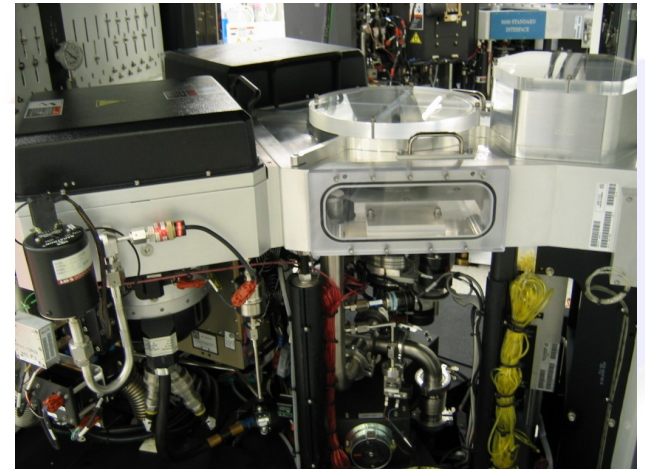


## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

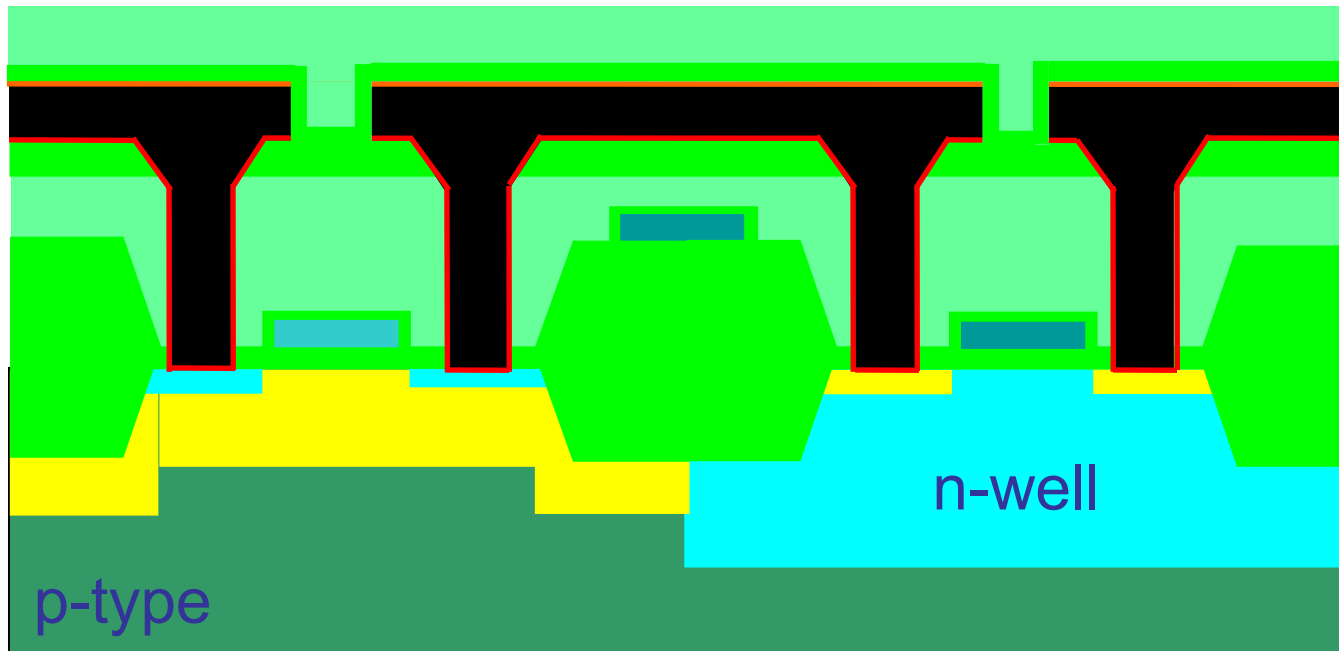
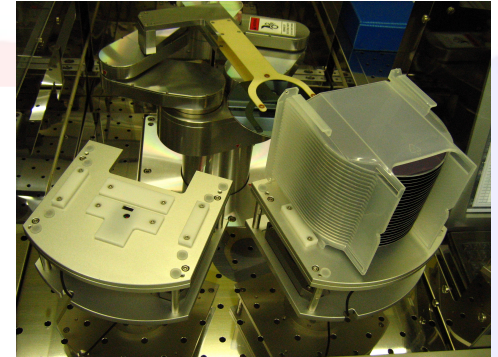
# Via and Metal2

Plasma oxide deposition



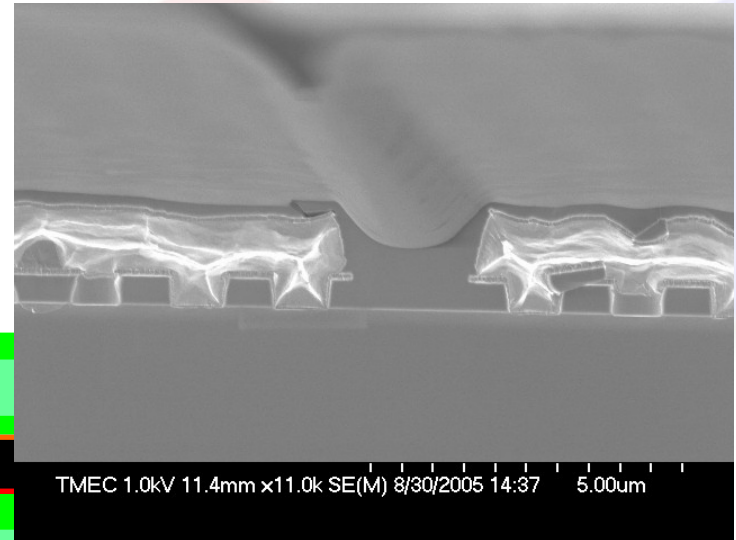
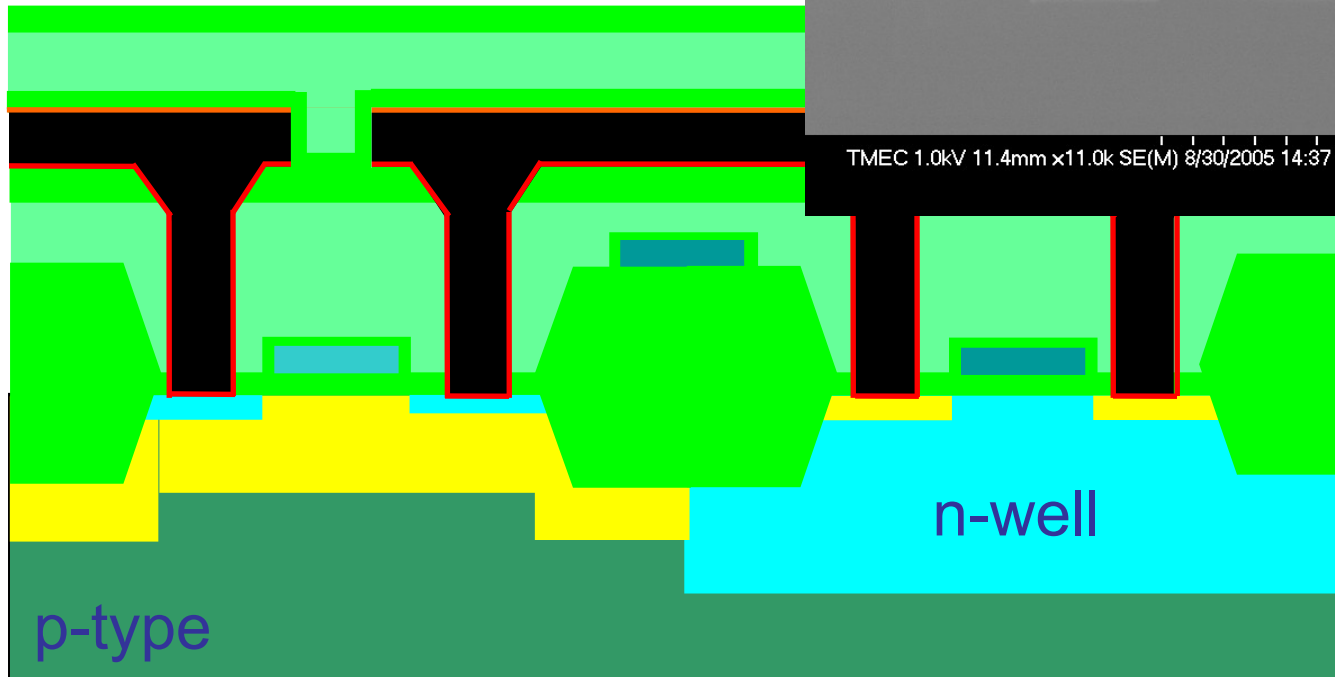
# Via and Metal2

SOG coat  
SOG cure



# Via and Metal2

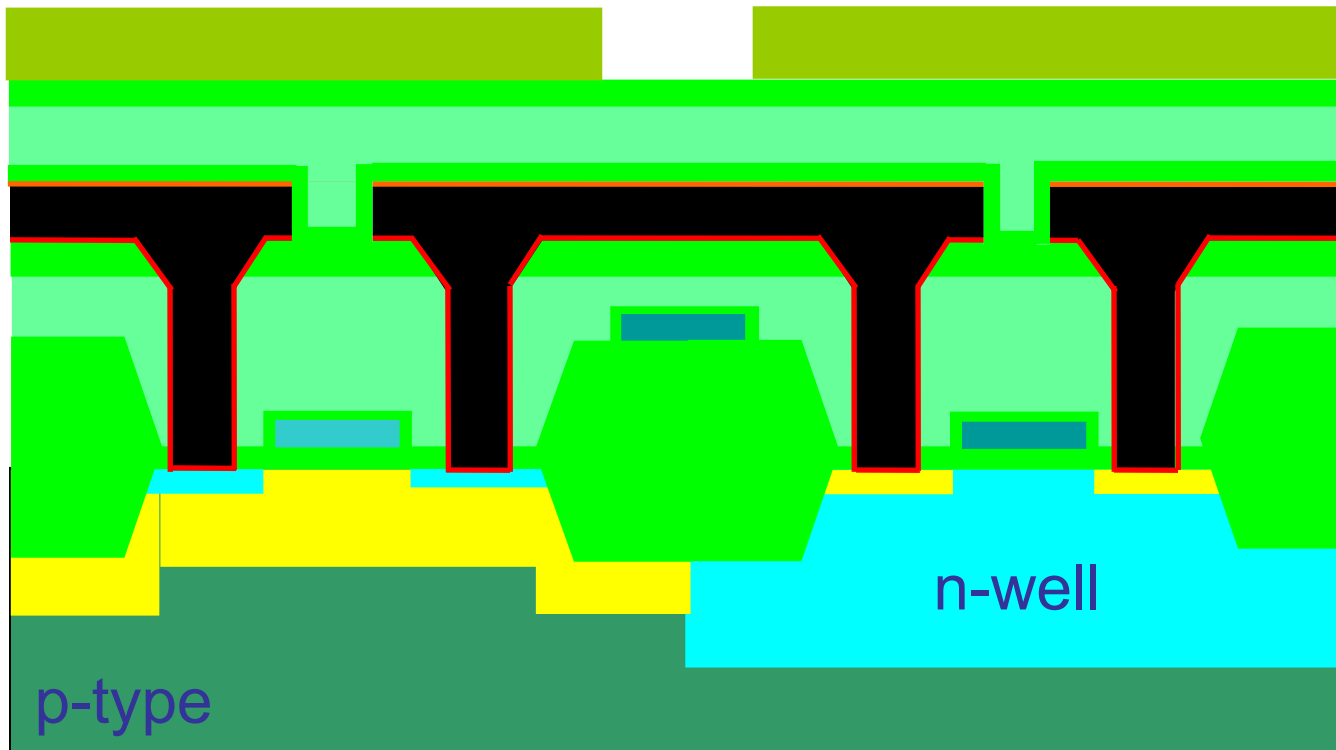
Plasma oxide deposition



# Via and Metal2



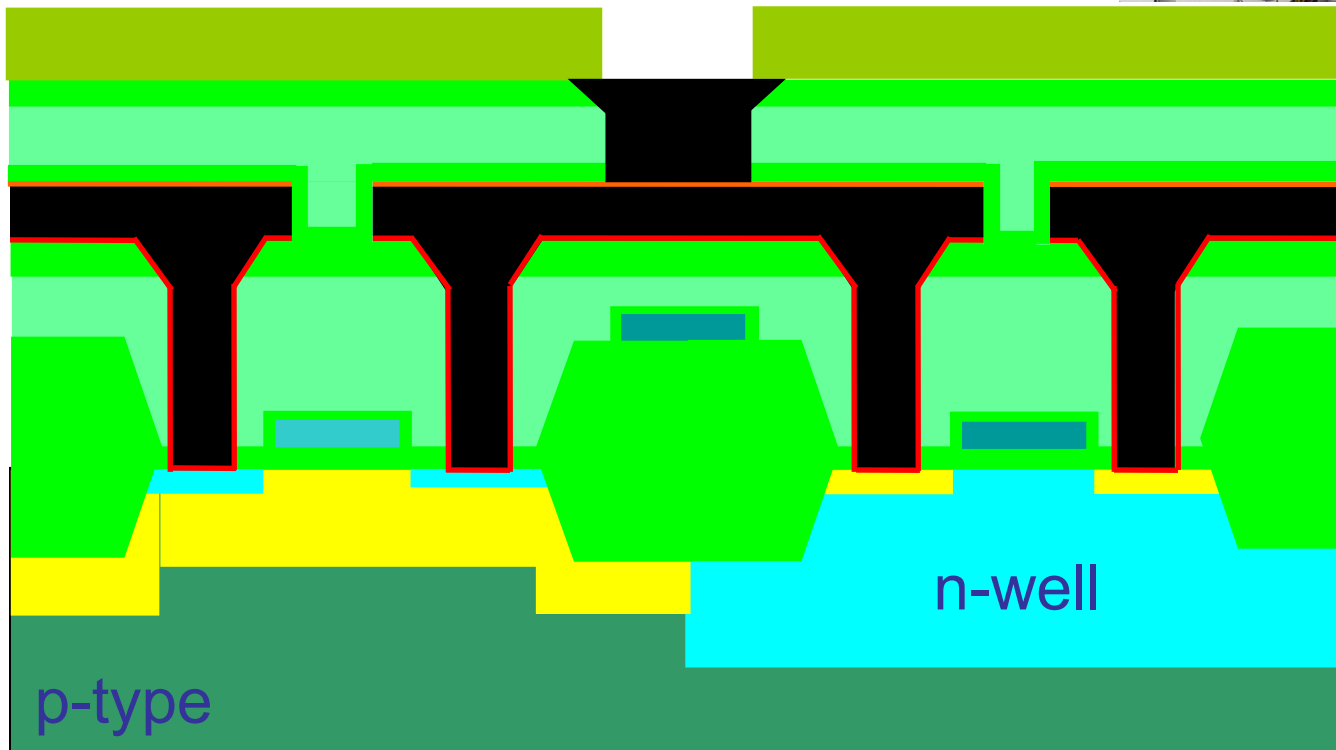
Photolithography : VIA



# Via and Metal2



Dry etch vias : isotropic + anisotropic

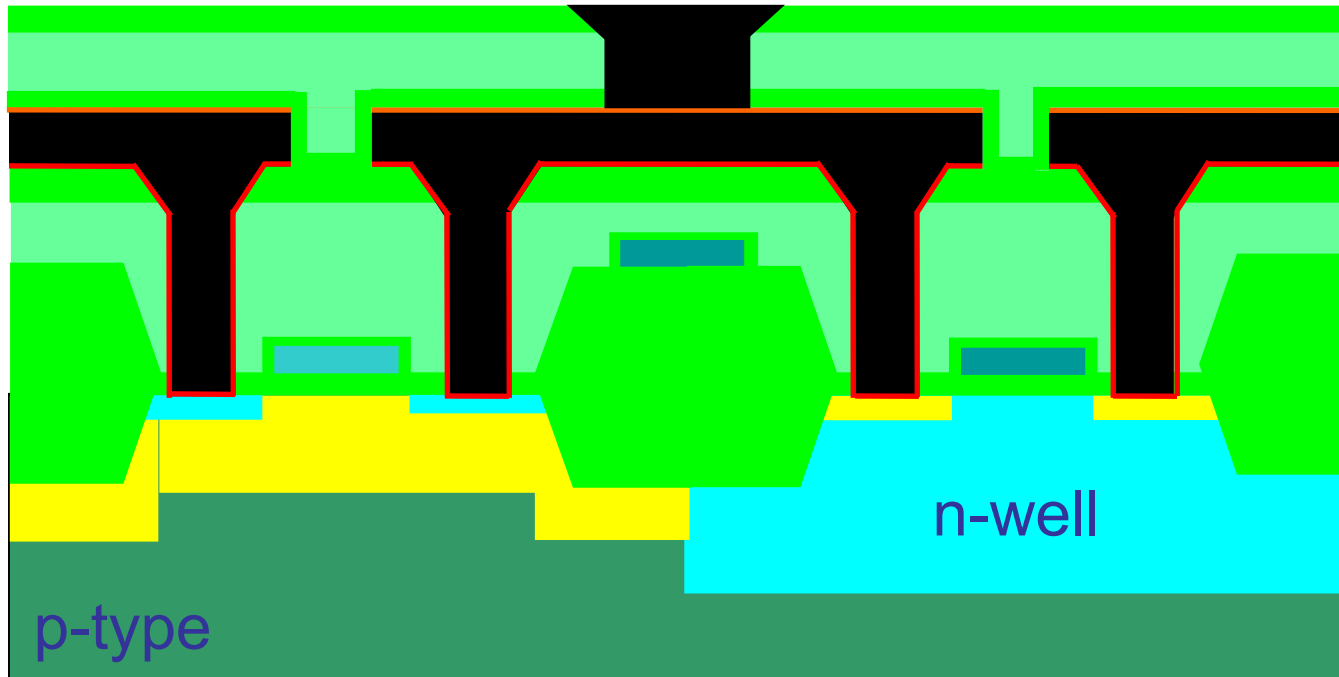




# Via and Metal2

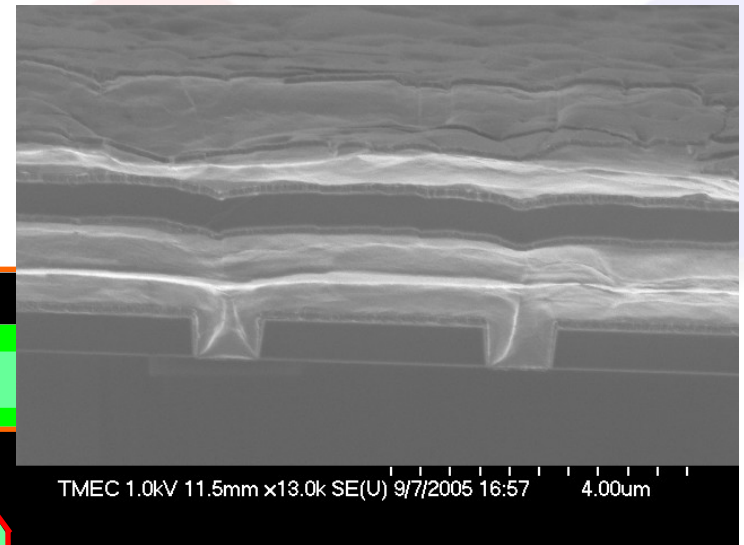
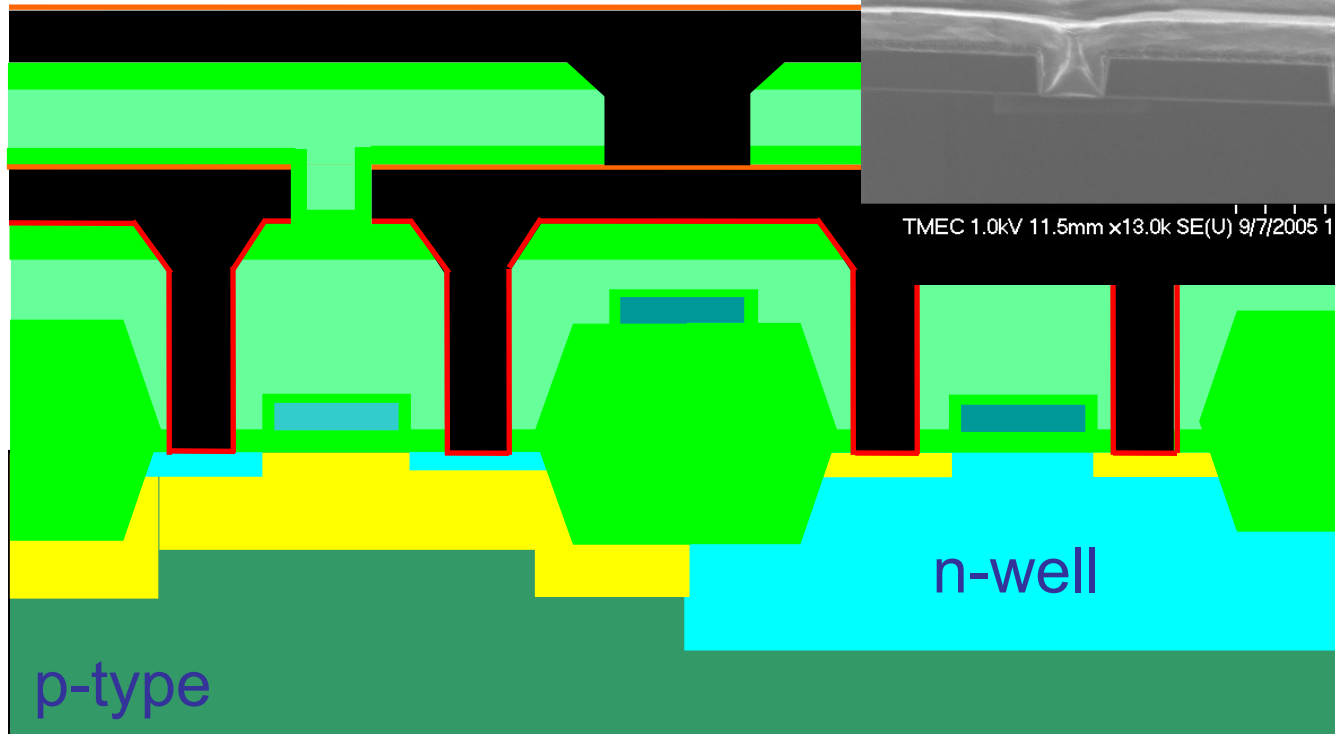


Resist strip



# Via and Metal2

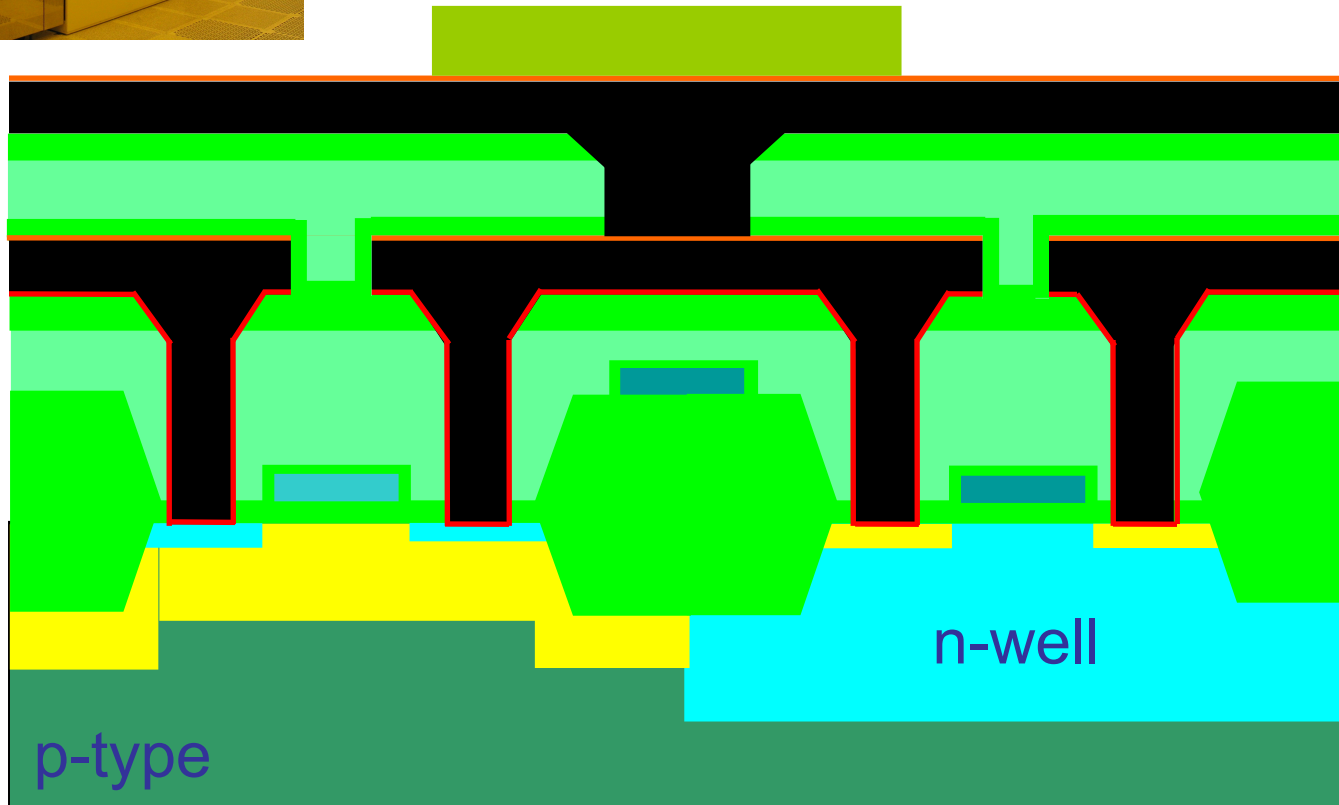
Metal2 sputtering : AlSiCu  
TiN



# Via and Metal2

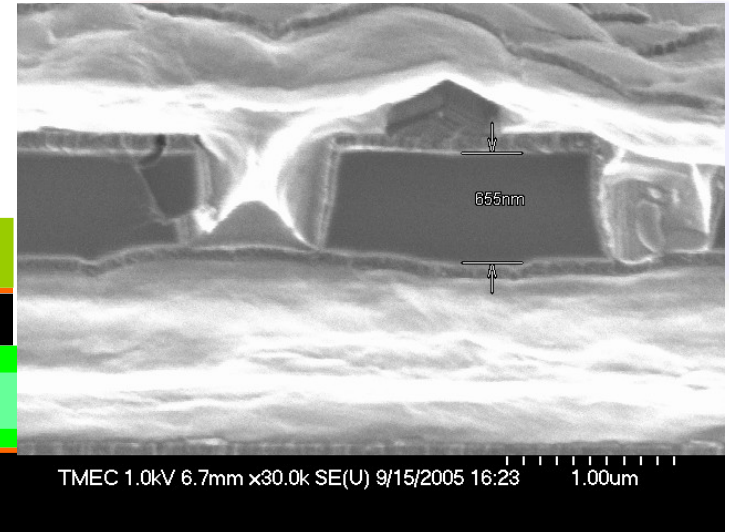
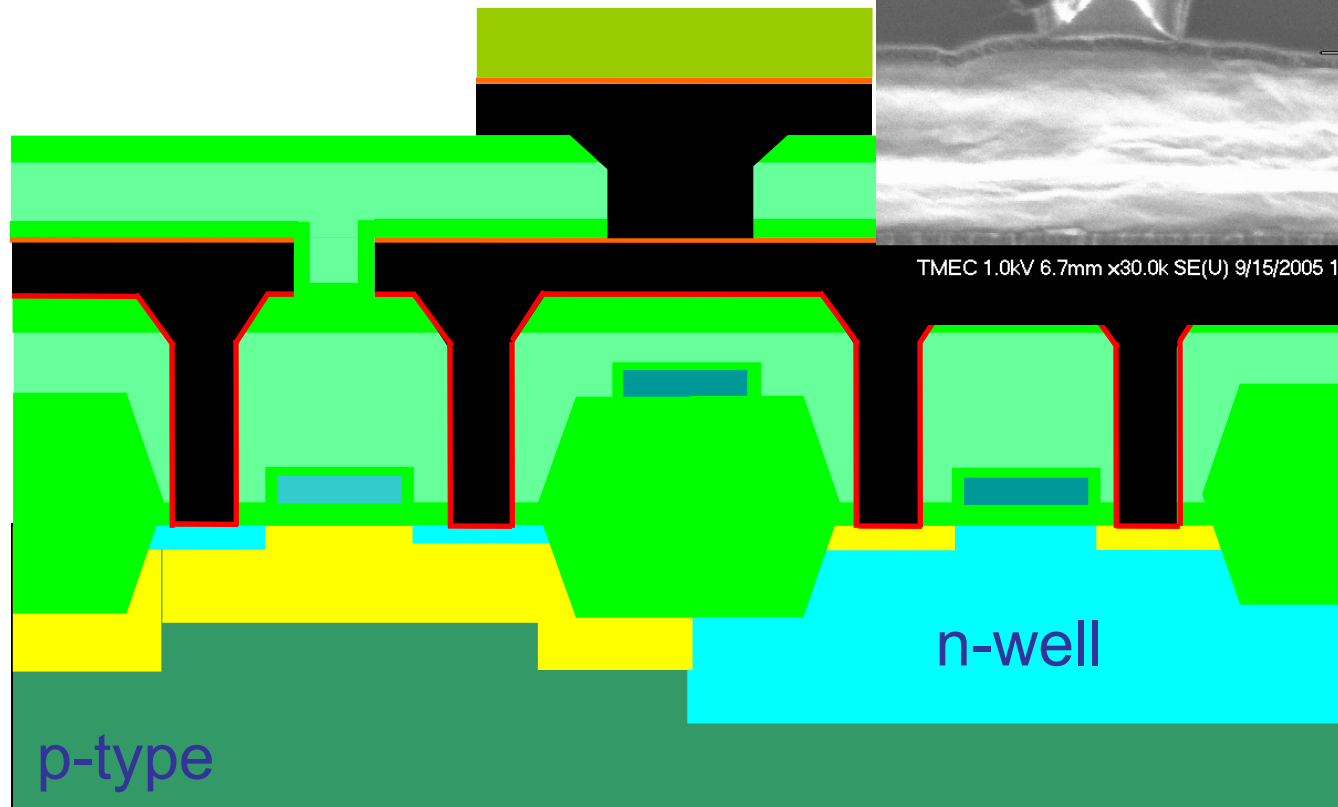


## Photolithography : METAL2



# Via and Metal2

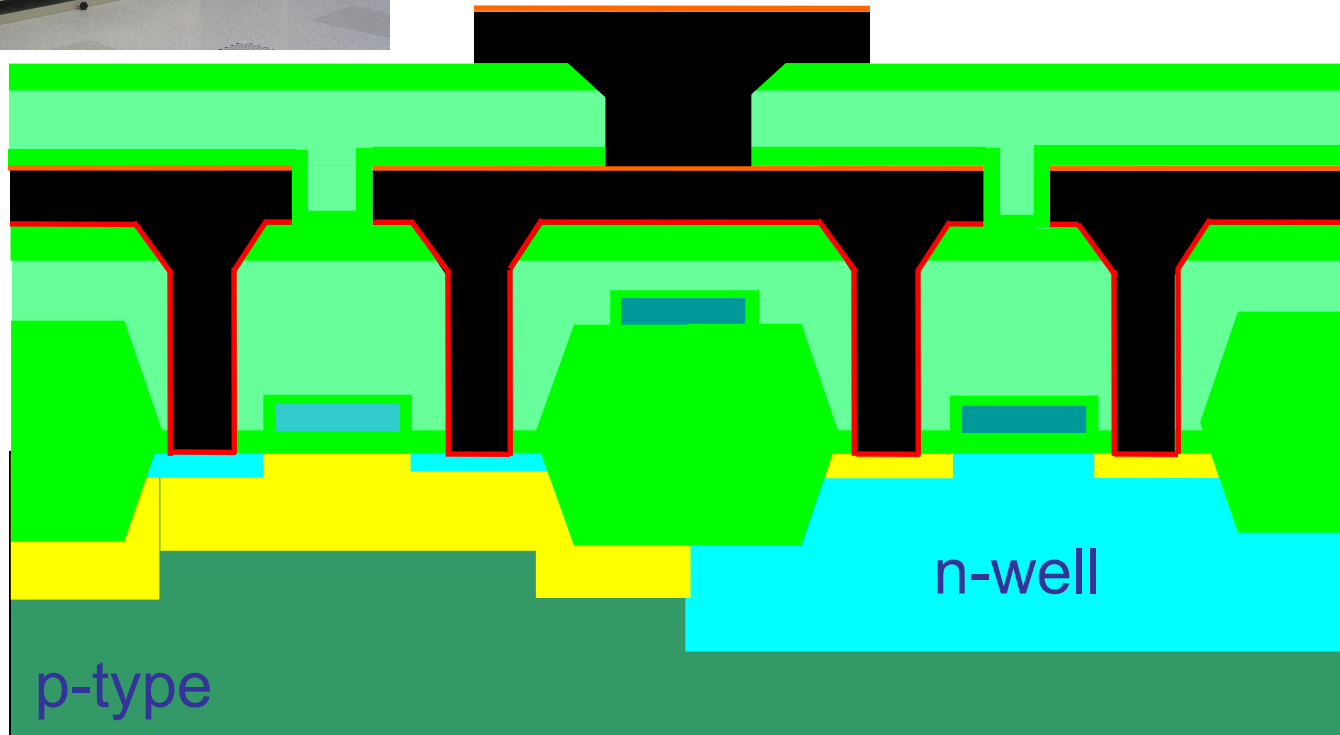
Dry etch metal2



# Via and Metal2



Resist strip



## p-type Silicon Substrate

1. Starting wafer
2. n-well
3. Active
4. Gate
5. Junction
6. ILD
7. Contacts and metal 1
8. Vias and metal 2
9. Passivation

PECVD nitride deposition, Photolithography : PASS,  
Dry etch nitride, Resist strip, Sintering : Forming gas

